



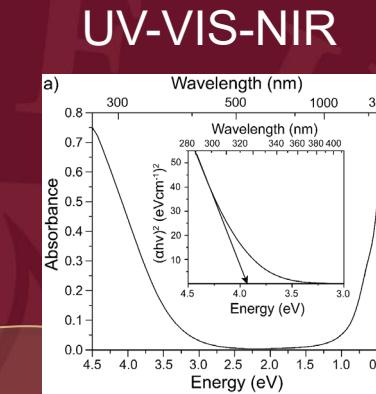
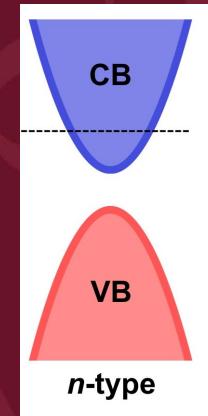
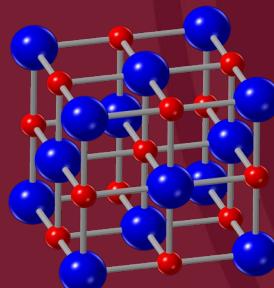
FLORIDA STATE
UNIVERSITY

Plasmonic Metal Oxide Nanocrystals

How a Semiconductor acts like a metal

Geoffrey F. Strouse

gstrouse@fsu.edu

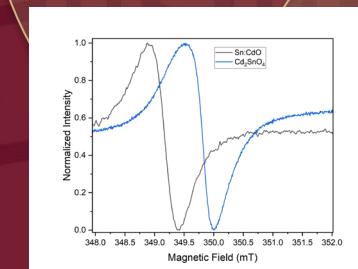


Defect Engineering

$V_{M/O}$,

M/O_i

M_2M_1 (antisite)



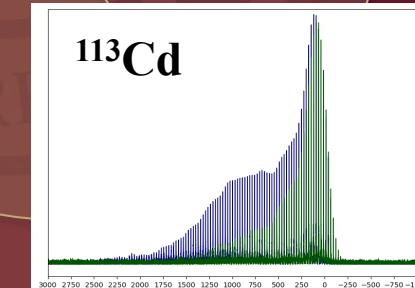
EPR

carrier density

$n \sim 10^{19} - 10^{21}$ carriers / cm³



^{113}Cd



NMR

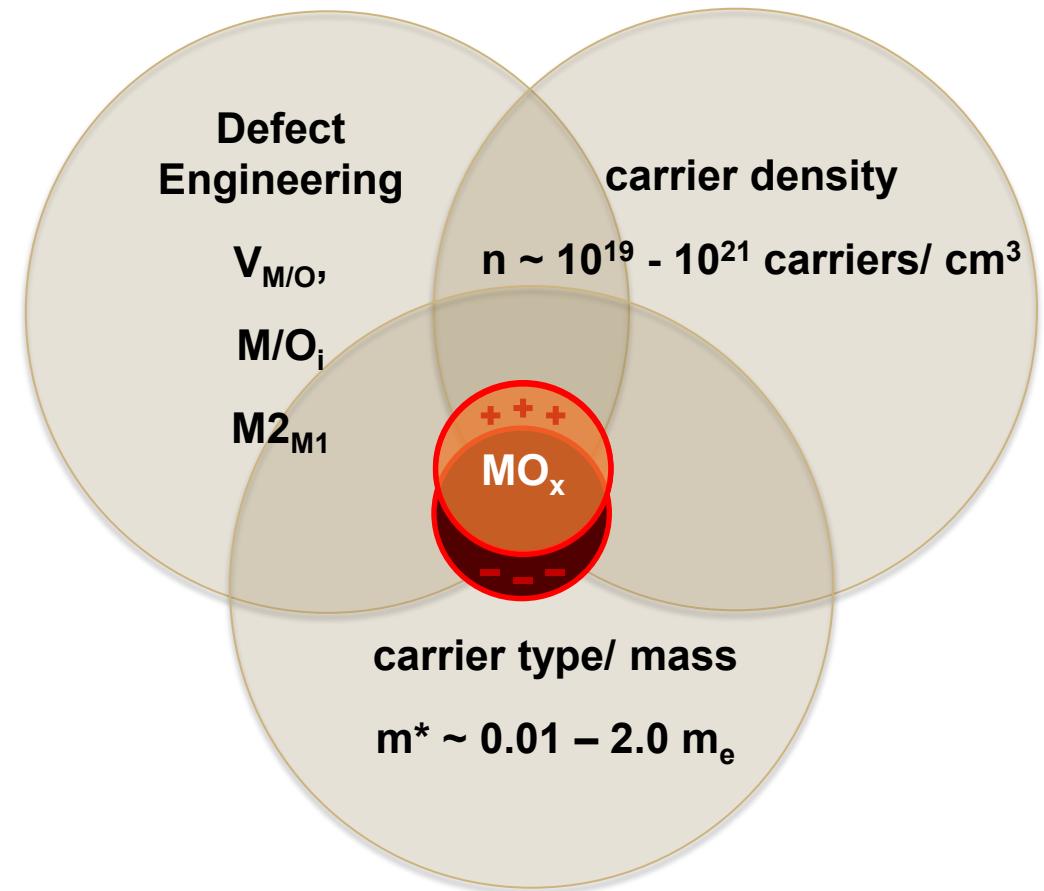
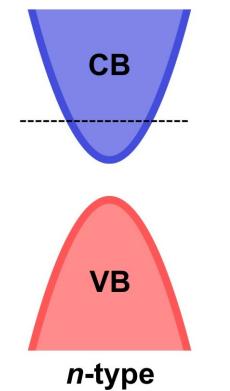
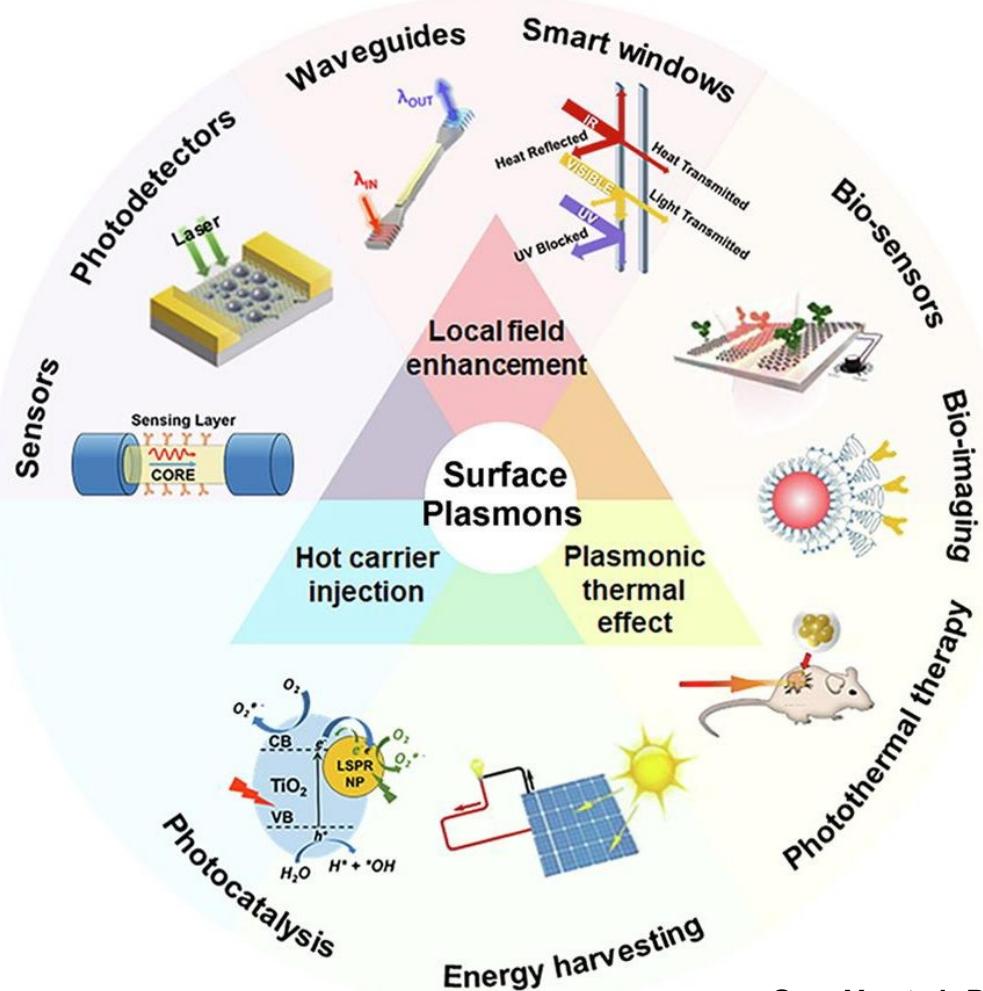
carrier type/ mass

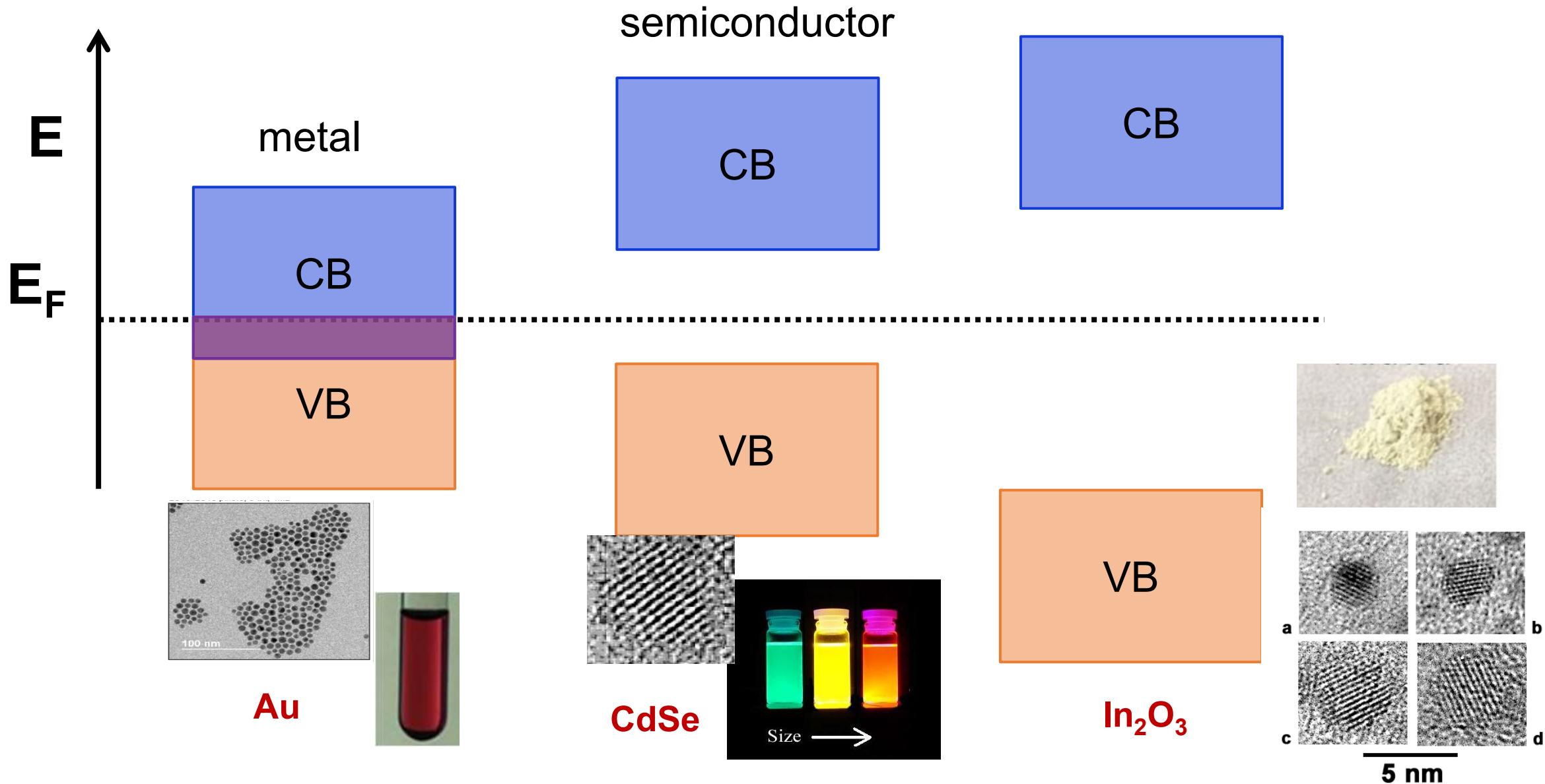
$m^* \sim 0.01 - 2.0 m_e$

NSF-DMR #1905757



Plasmonic MO_x Semiconductor Nanocrystals



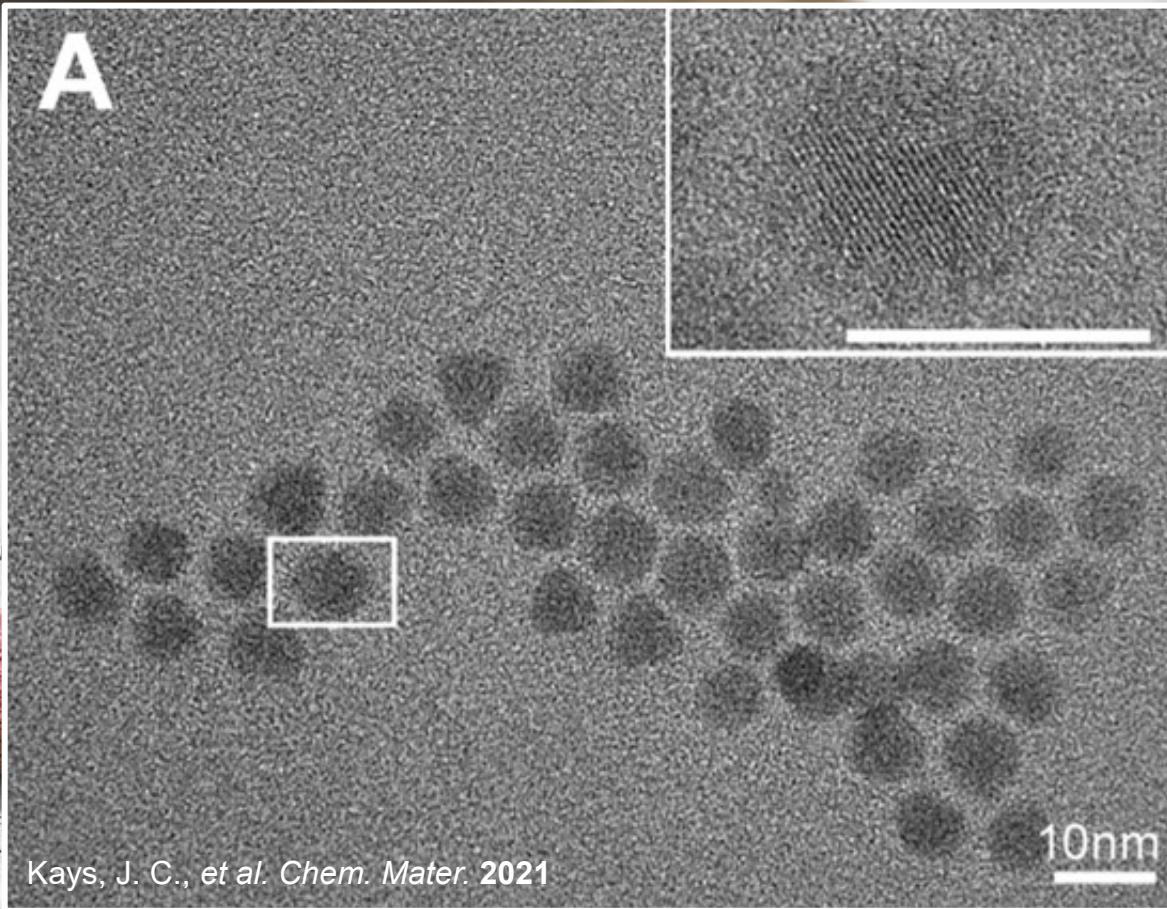
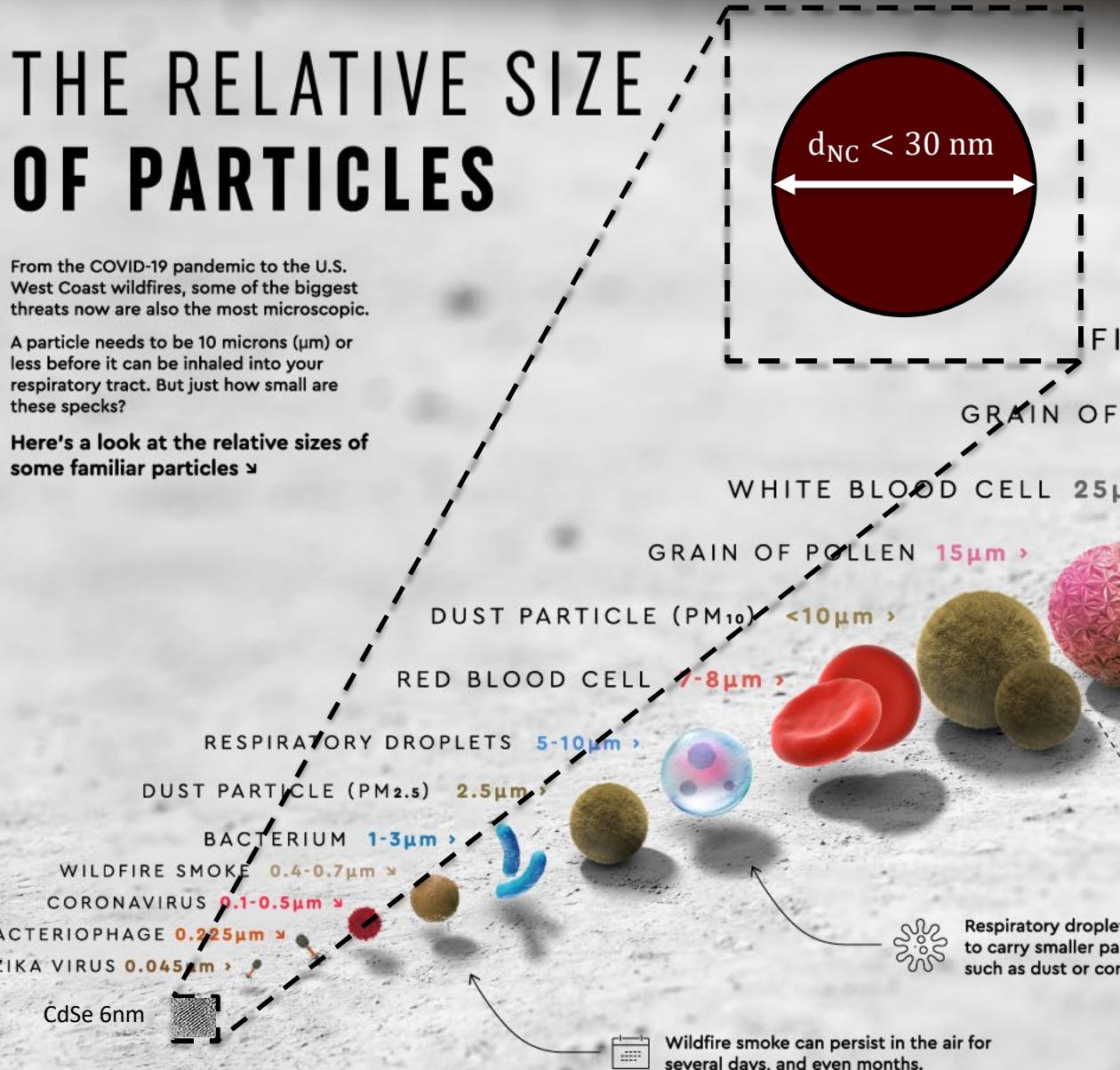


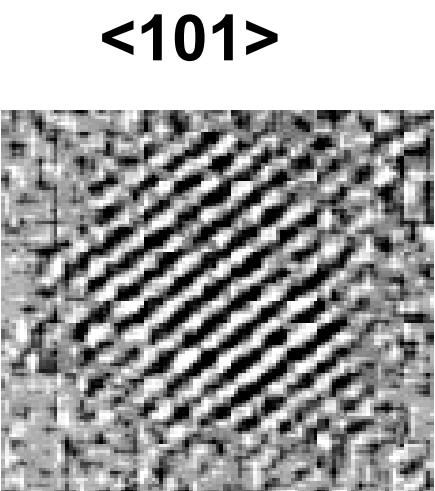
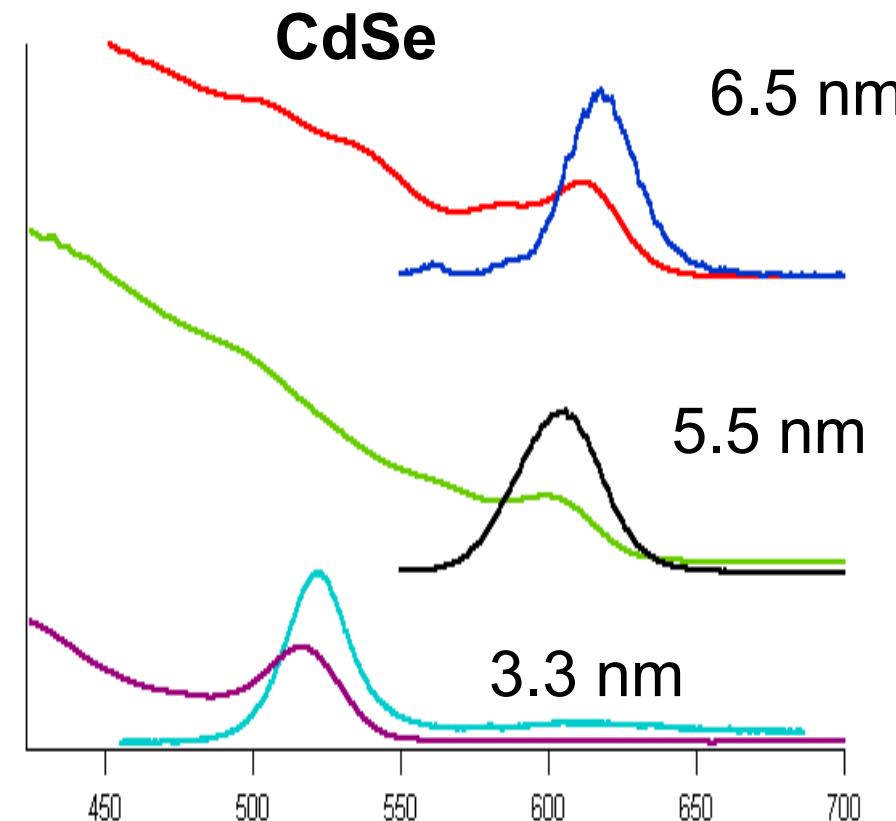
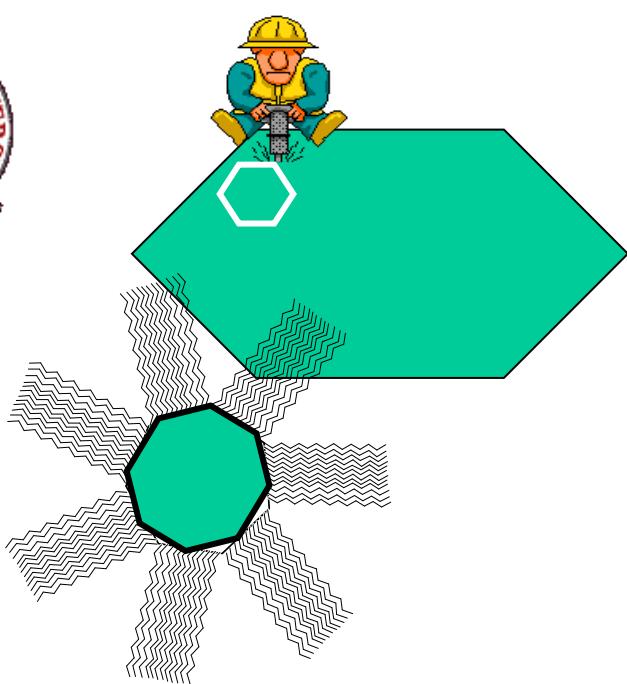
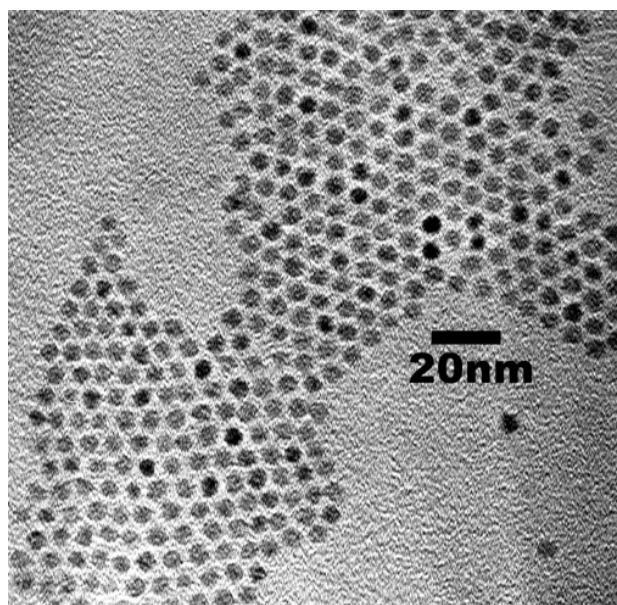
THE RELATIVE SIZE OF PARTICLES

From the COVID-19 pandemic to the U.S. West Coast wildfires, some of the biggest threats now are also the most microscopic.

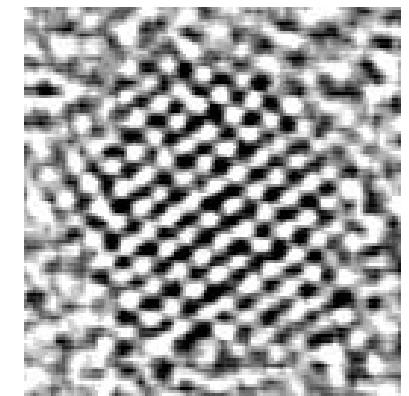
A particle needs to be 10 microns (μm) or less before it can be inhaled into your respiratory tract. But just how small are these specks?

Here's a look at the relative sizes of some familiar particles ↴

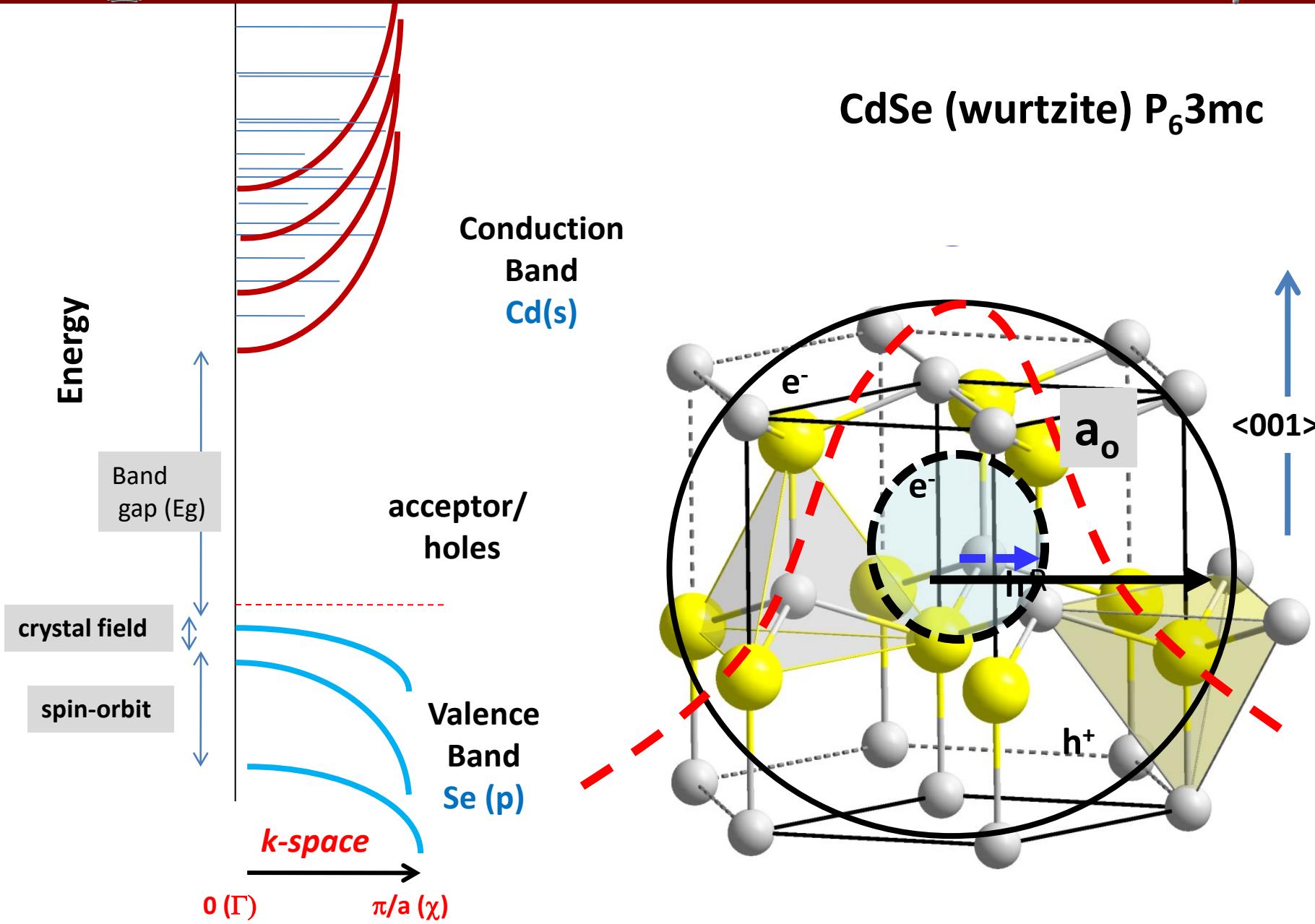




$<002>$

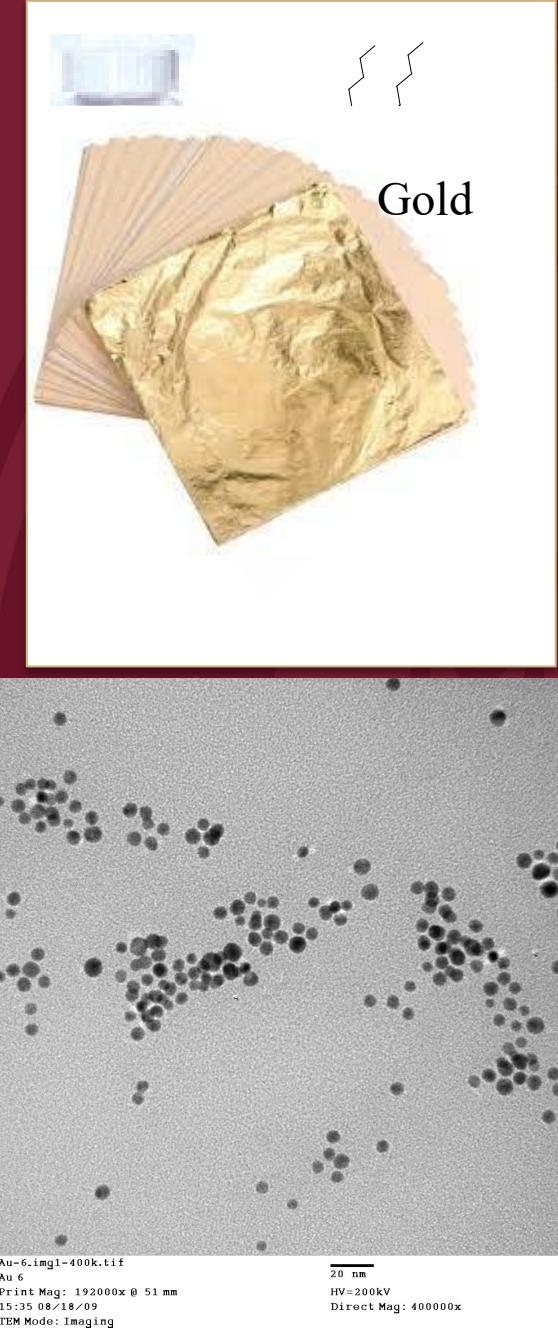
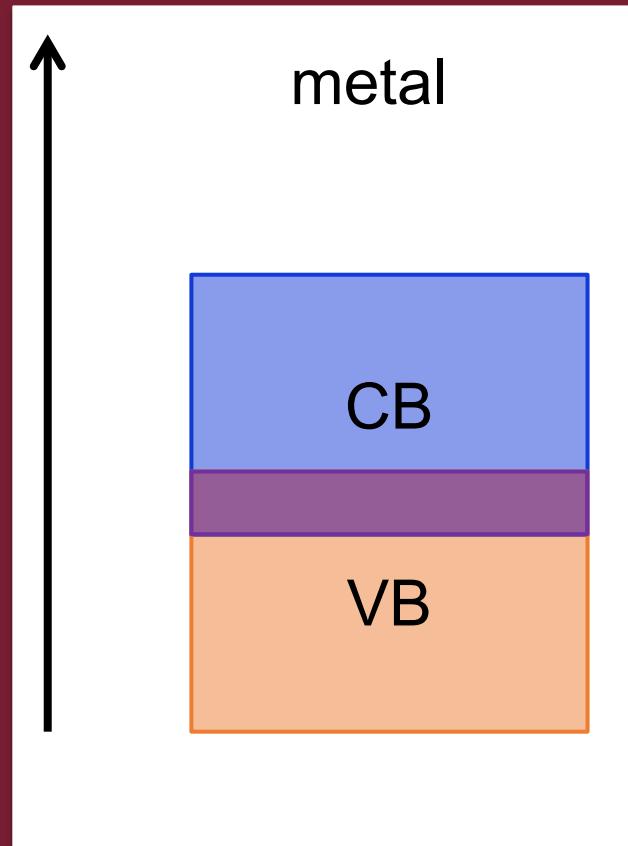


5 nm

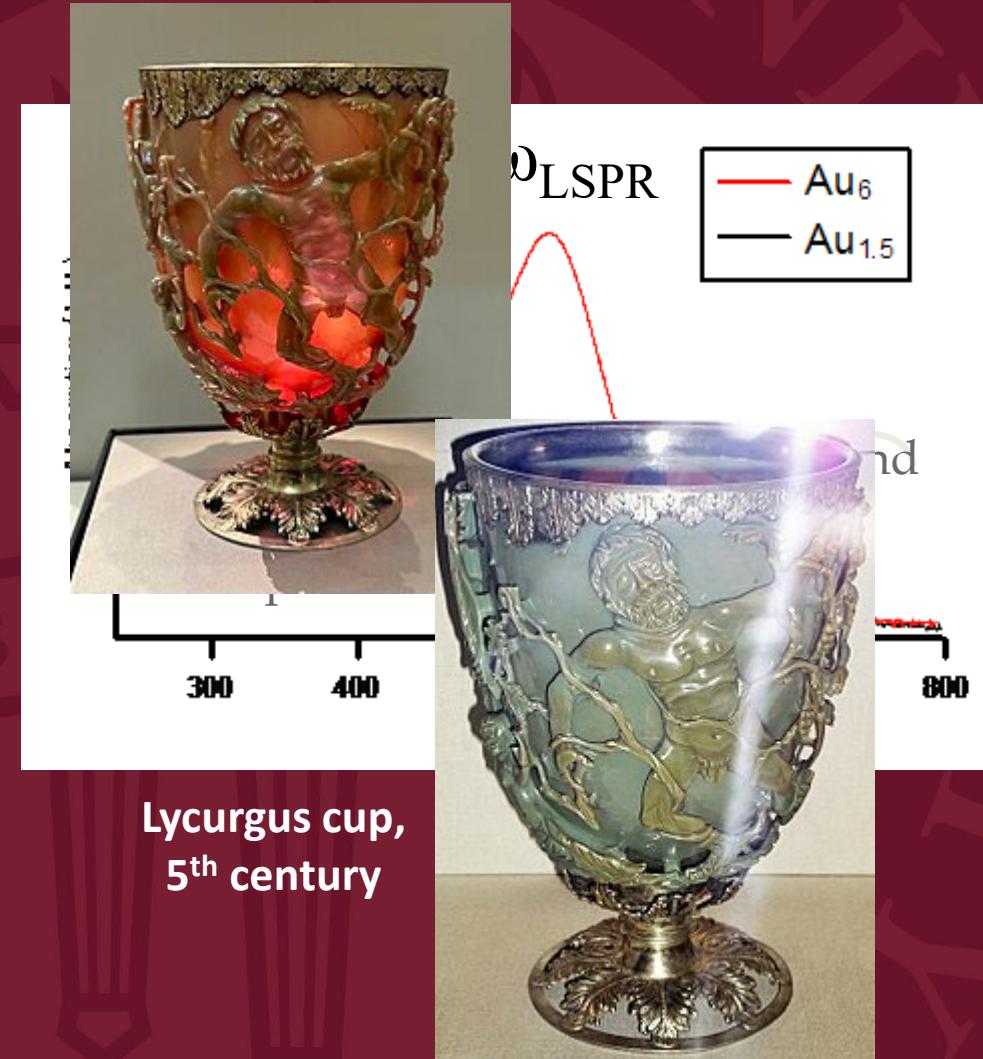




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LSPR Extinction Spectra for Au





Plasmons, Photons, and Permittivity, Oh my

The Dielectric Function

(relative permittivity)

$$\epsilon_r(\omega) = \epsilon'_r(\omega) + i\epsilon''_r(\omega)$$

$\epsilon_r(\omega)$ describes the interactions of materials with applied electric fields.

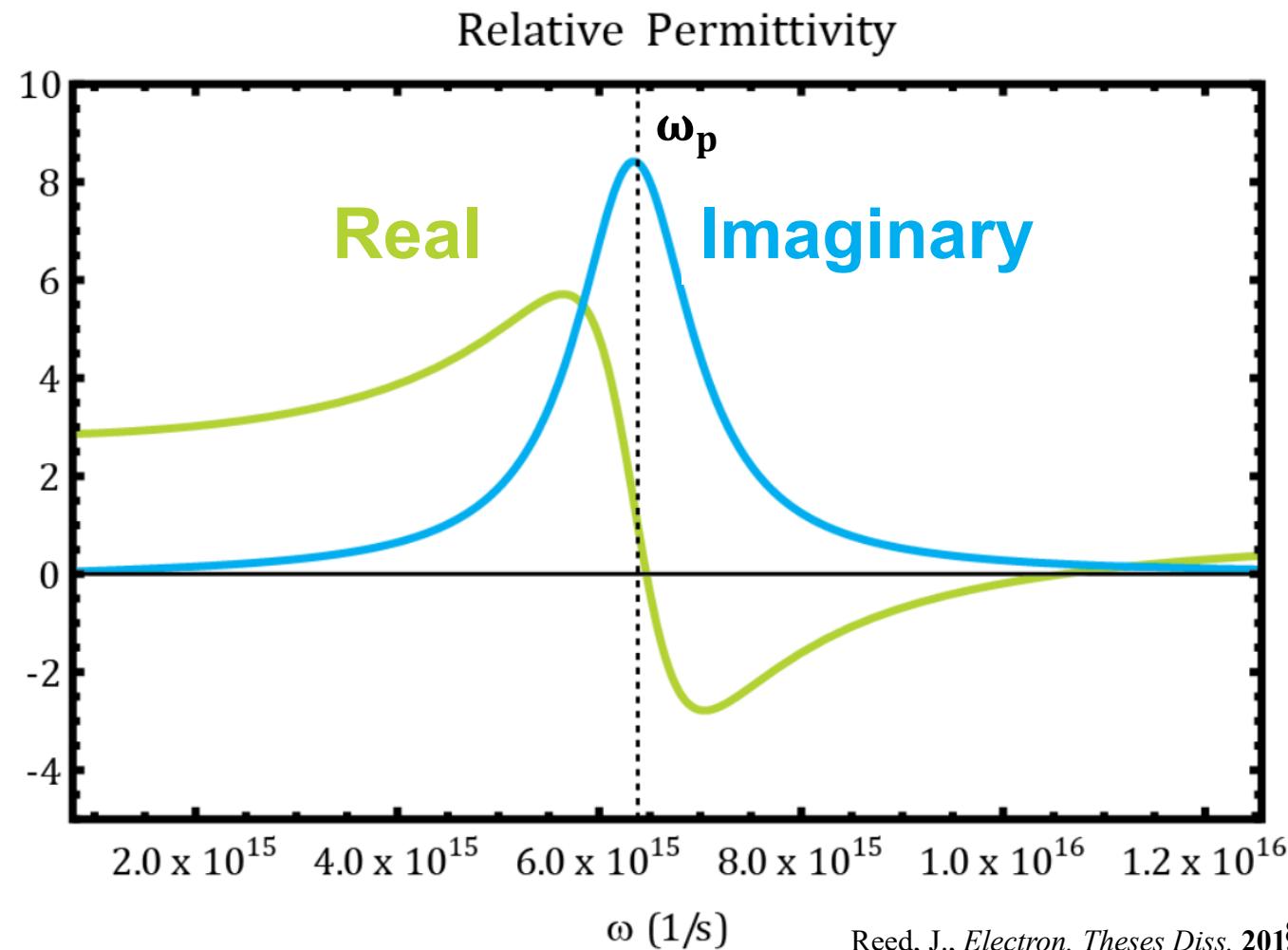
$$\epsilon_r(\omega) = \epsilon_\infty - \frac{\omega_p^2}{\omega^2 + i\omega\Gamma}$$

$\underbrace{\hspace{1cm}}$
size dependent damping

$$\omega_p^2 = \frac{ne^2}{\epsilon_0 m^*}$$

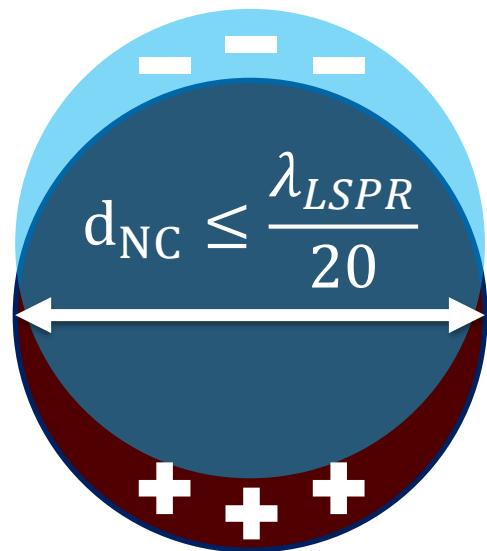
Maximum extinction arises at maximum ϵ''_r .

Here, a resonance condition is met



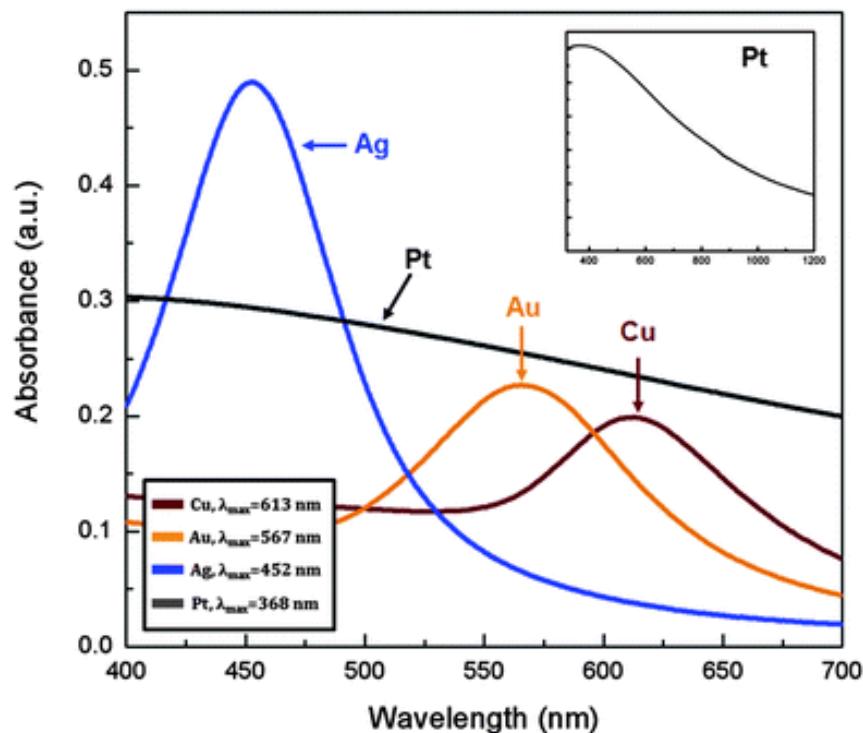


Metals: Localized Surface Plasmon Resonance (LSPR)



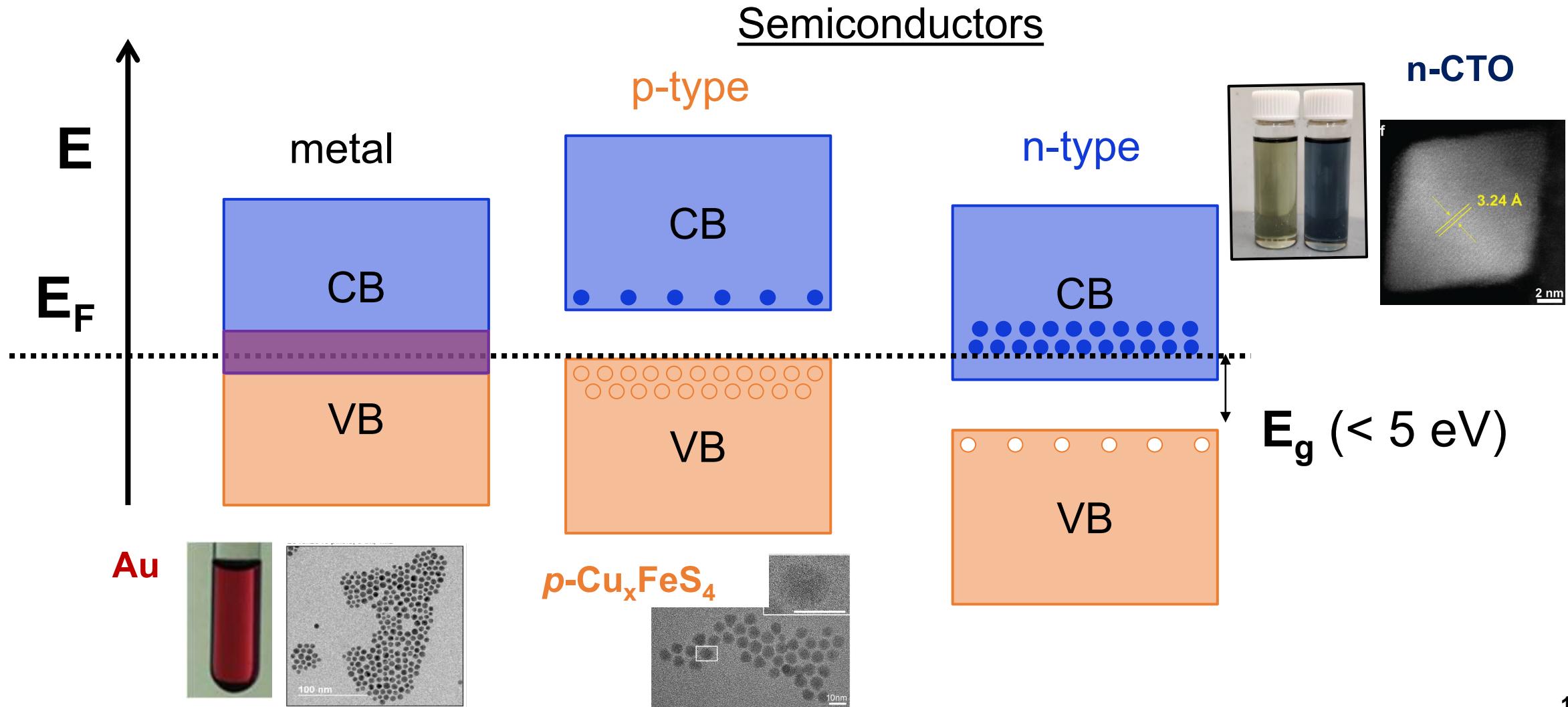
Nobel Metals (metallic)

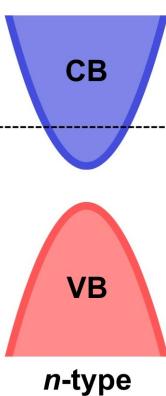
Shin, D. O., et al., *J. Mater. Chem.*, 2010



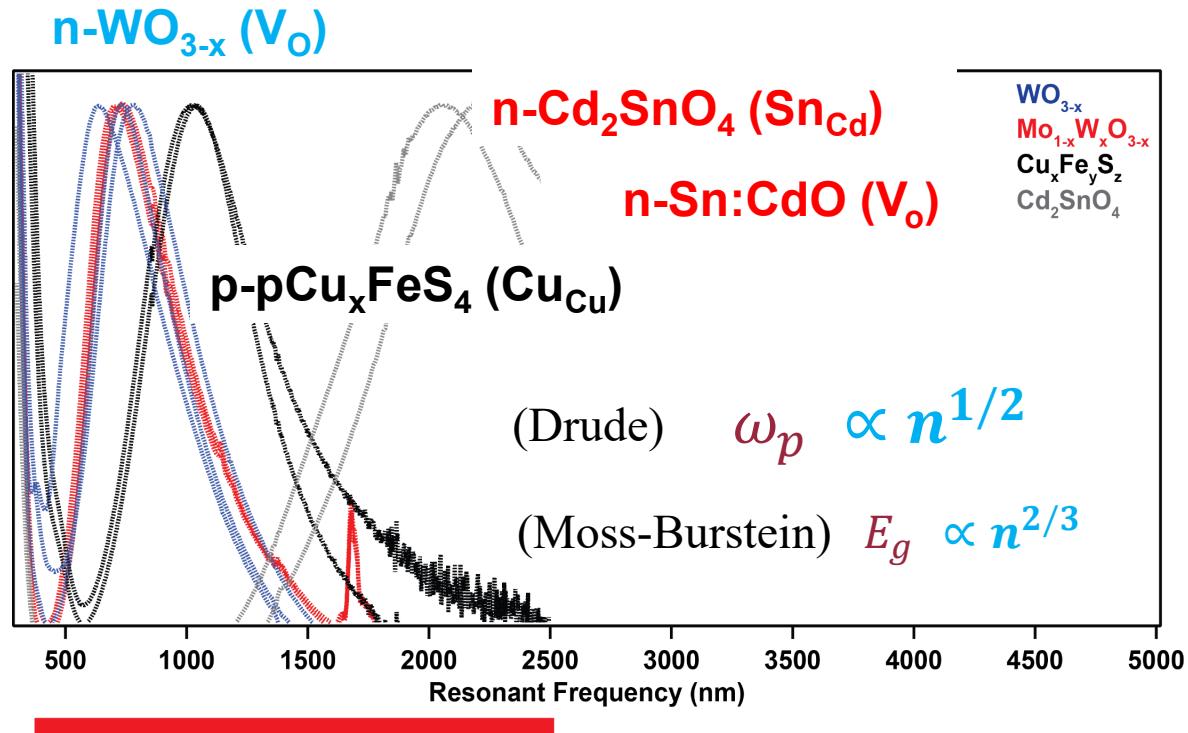


Plasmons require carriers (or electrons) above the Fermi Energy Level





Plasmonic Semiconductor Nanocrystals (PSNC)

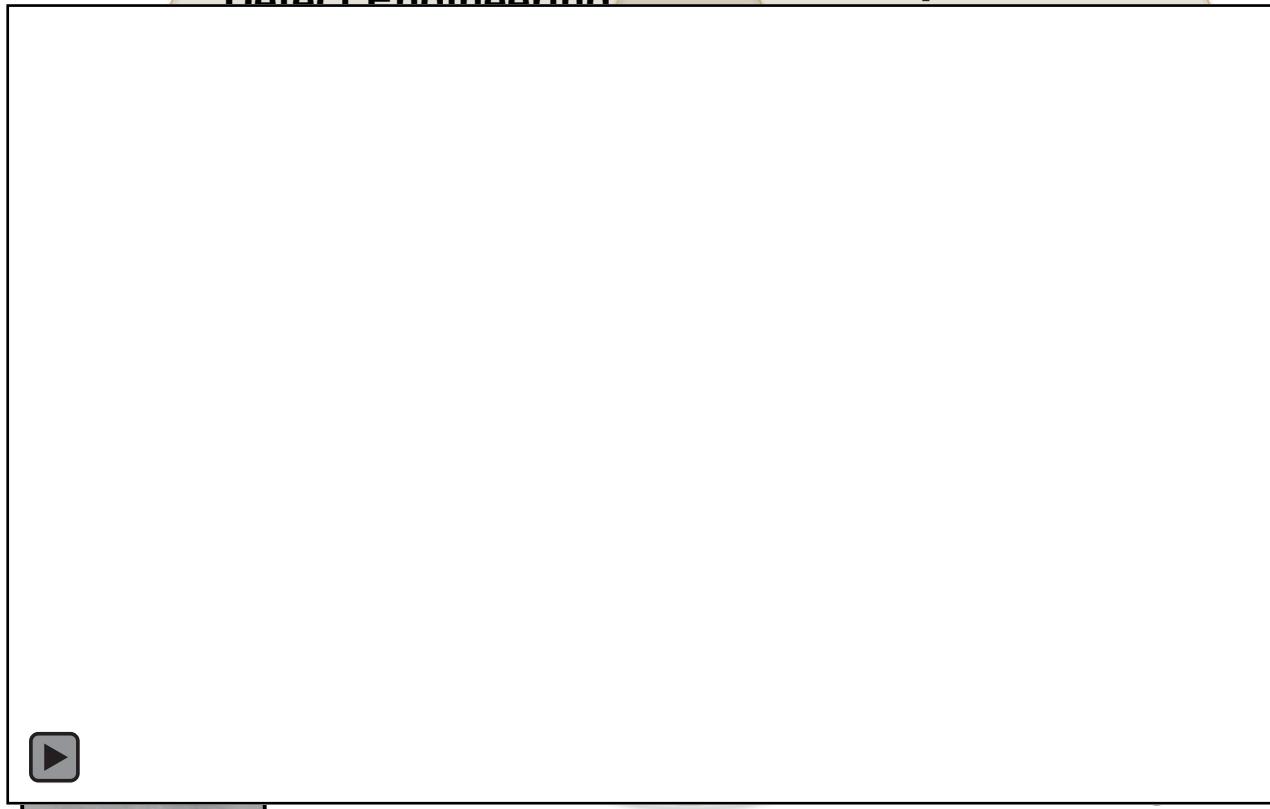


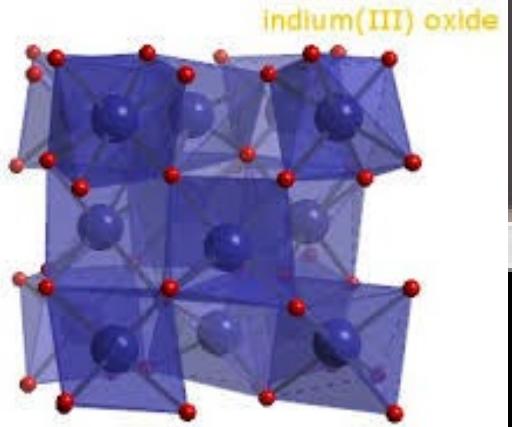
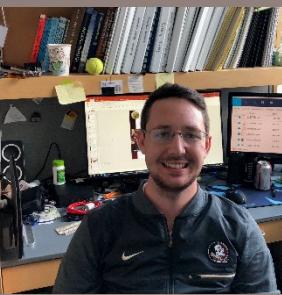
Solar Spectrum
Penetration of Biological Tissue
Night Vision
Telecommunication

Waste Heat Management

Collective oscillation of free carriers at a carrier density plasma frequency, ω_p

Defect Engineering





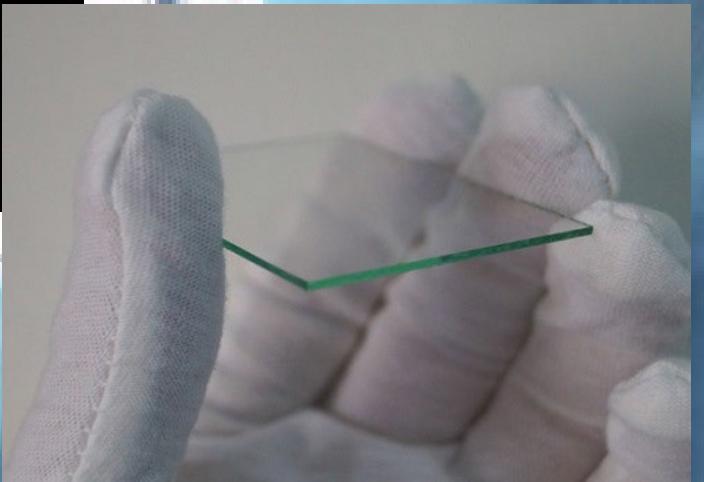
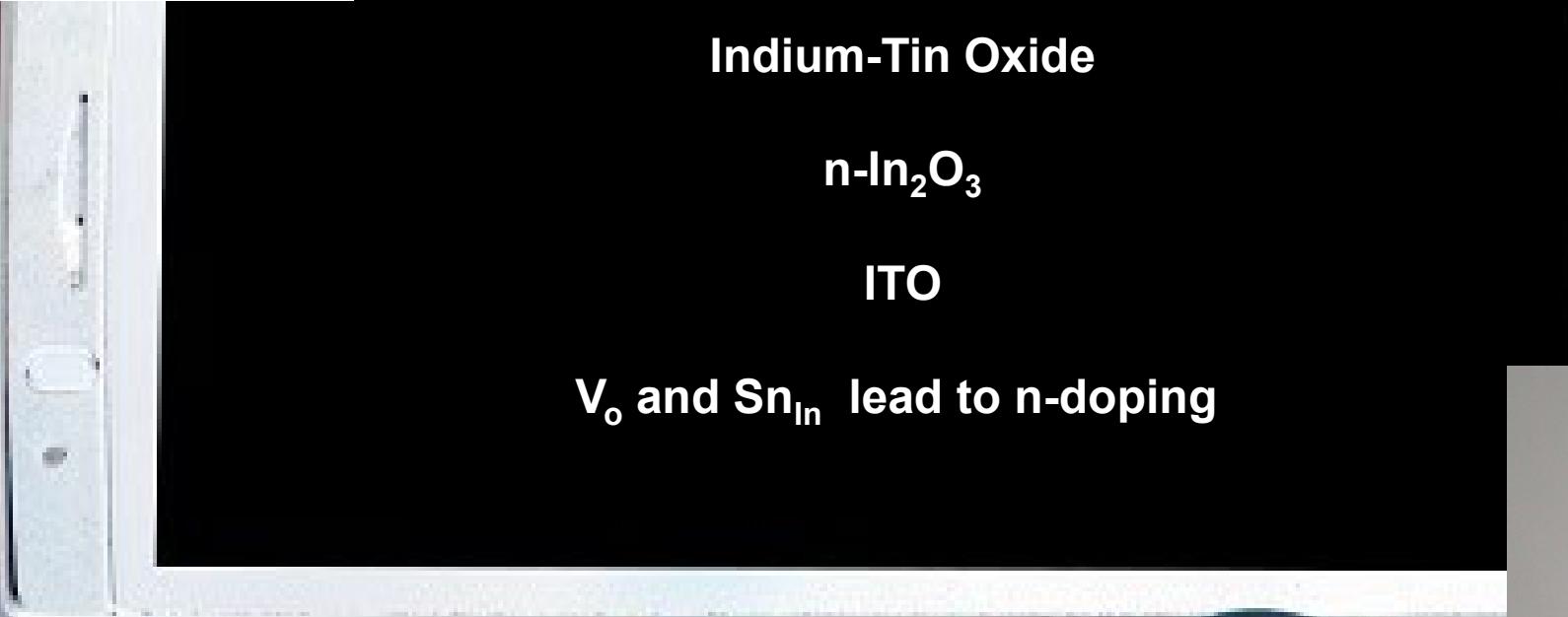
Conducting glass: an industrial standard

Indium-Tin Oxide

$n\text{-In}_2\text{O}_3$

ITO

V_o and Sn_{In} lead to n-doping



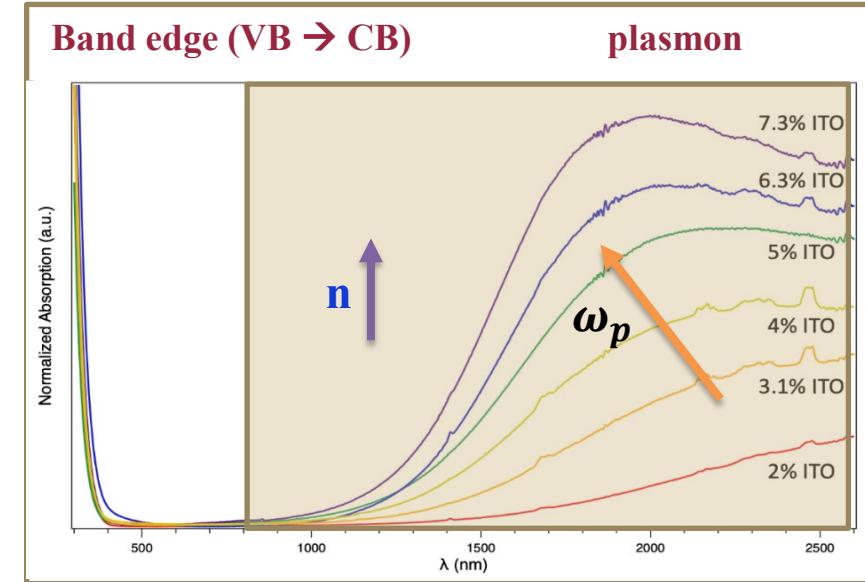
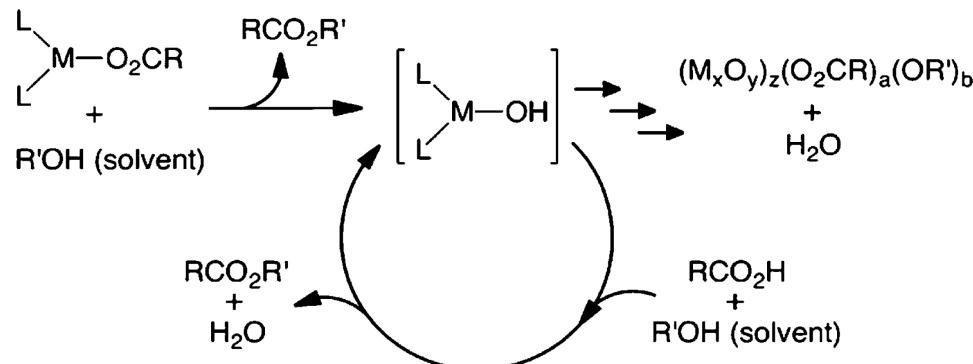


Carrier Density, Effective Mass, and Nuclear Relaxation Pathways in Plasmonic Sn:In₂O₃ Nanocrystals

Carl R. Conti III, Giovanni Quiroz-Delfi, Joanna S. Schwarck, Banghao Chen, and Geoffrey F. Strouse*

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Increasing Sn_{In}



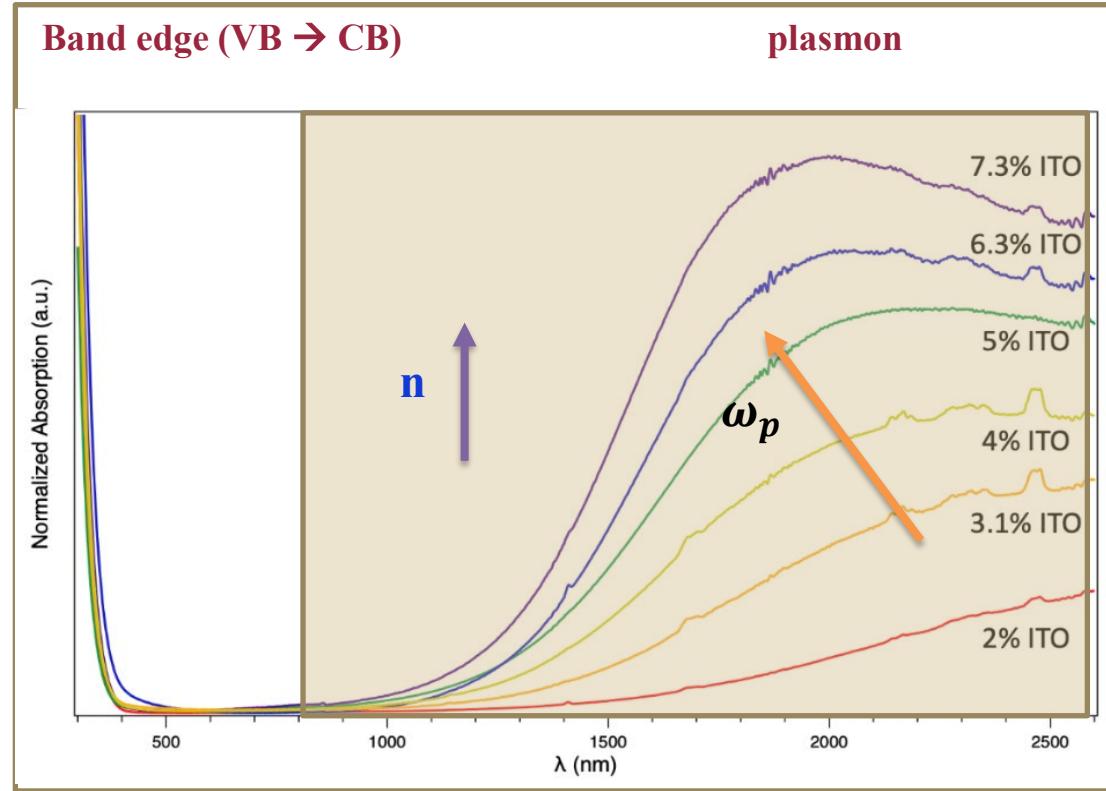


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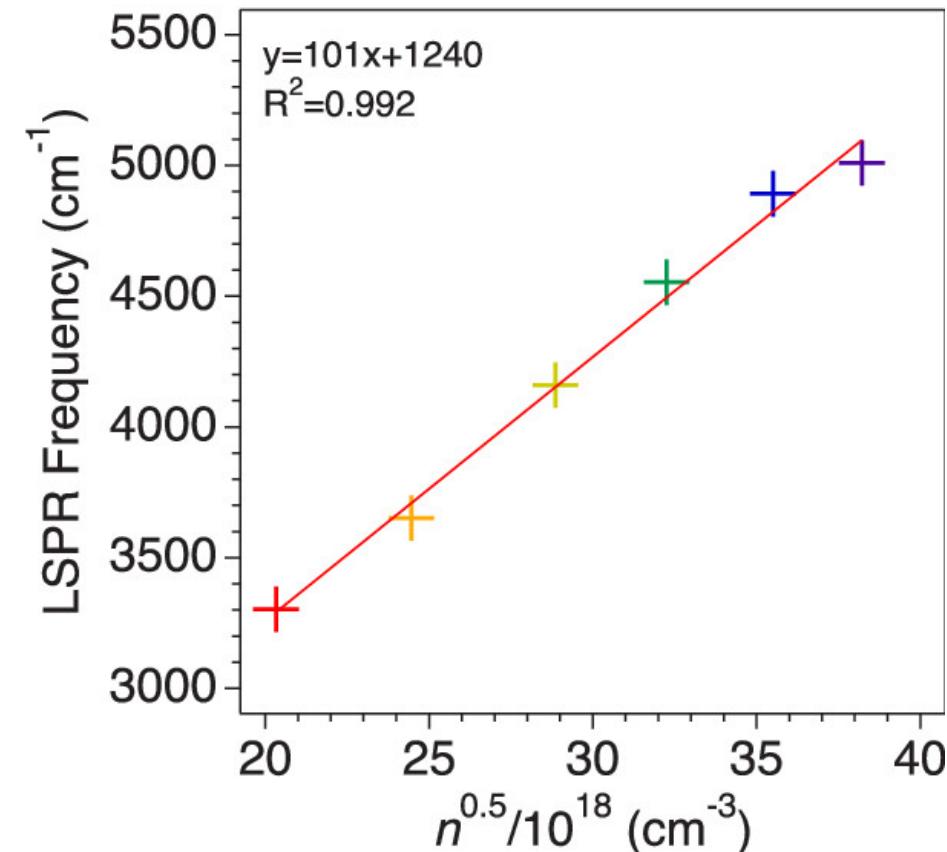
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(simplified) The Drude Model

$$\omega_p^2 = \frac{n e^2}{m^* \epsilon_0}$$

b.



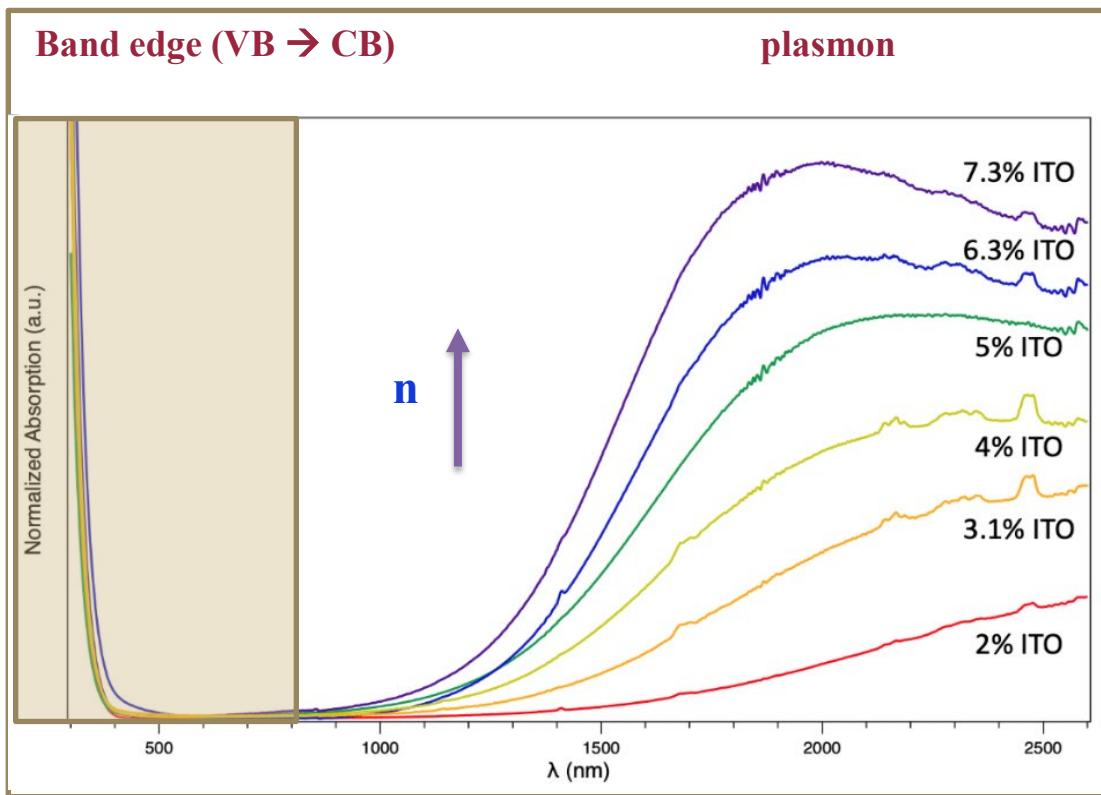


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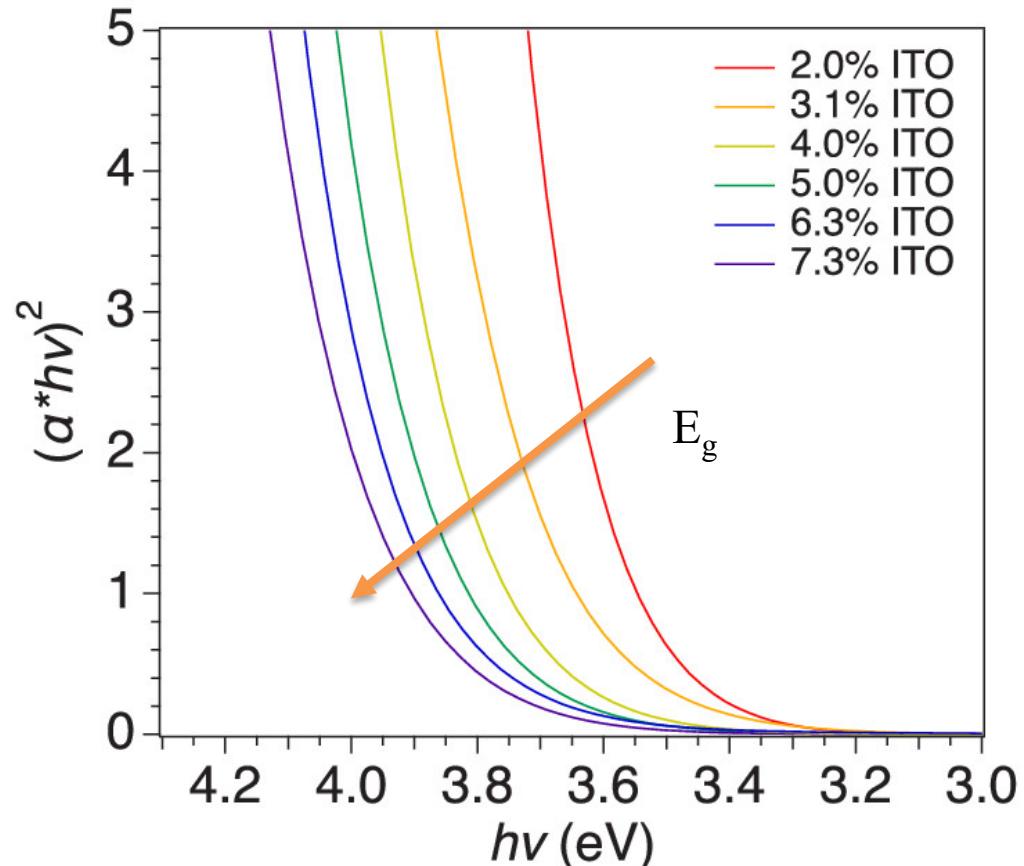
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Moss-Burstein (E_g)

$$\Delta E_{\text{abs}} = E_g^{\text{Sn}} - E_g^0 = \left(\frac{\hbar^2}{2m^*} \right) (3\pi^2 n)^{2/3}$$

a.

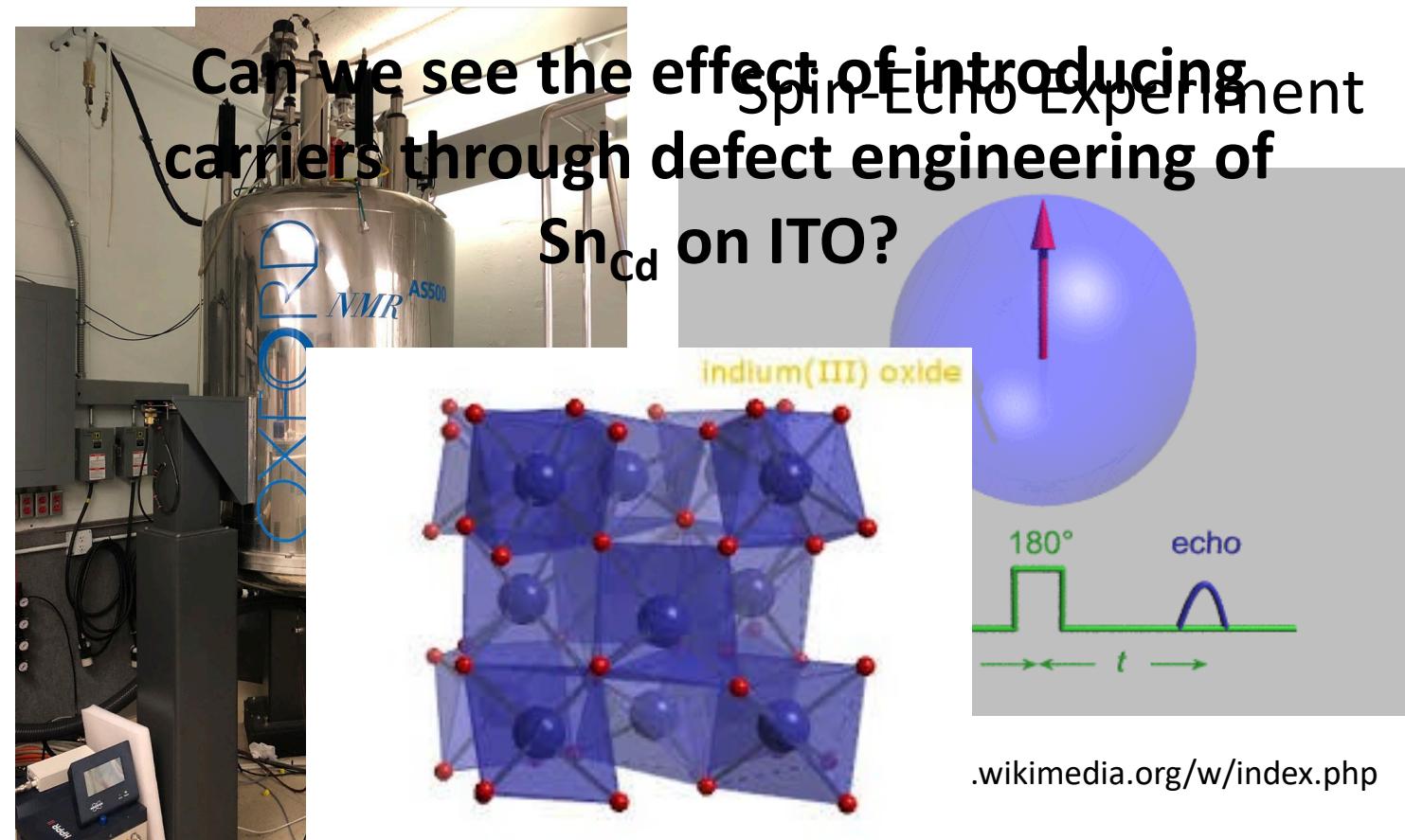
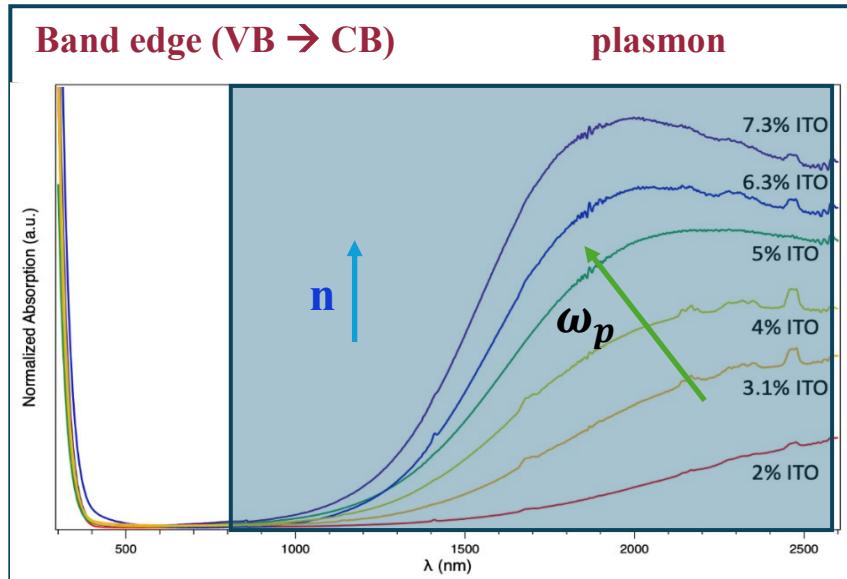


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Carl R. Conti III, Giovanni Quiroz-Delfi, Joanna S. Schwarck, Banghao Chen, and Geoffrey F. Strouse* **119**Sn MAS Solid-State NMR

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Bruker AVIII HD 500
MHz WB NMR



Carrier Density, Effective Mass, and Nuclear Relaxation Pathways in Plasmonic Sn:In₂O₃ Nanocrystals

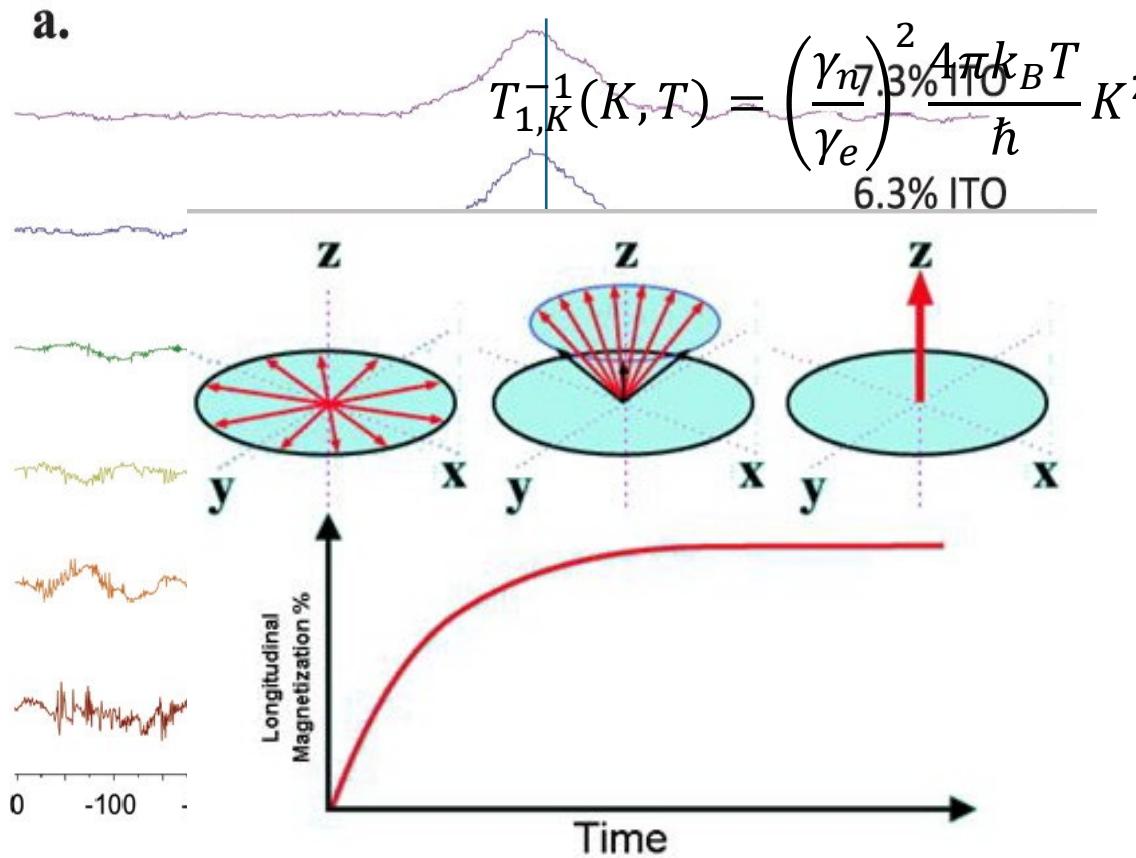
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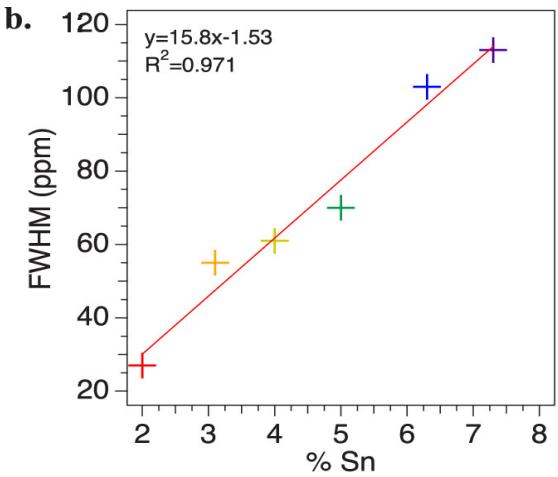
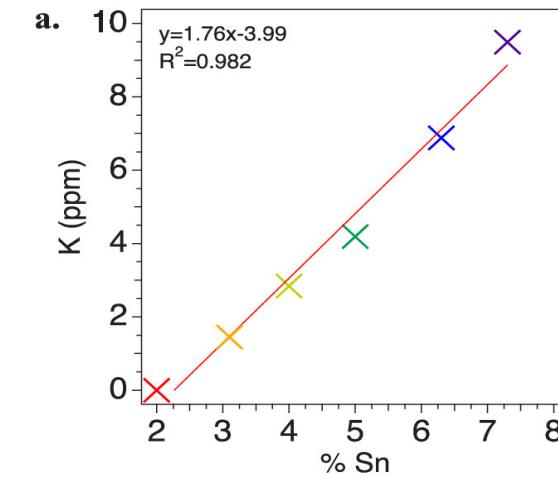
¹¹⁹Sn MAS ssNMR spin-echo

Knight-Korringa

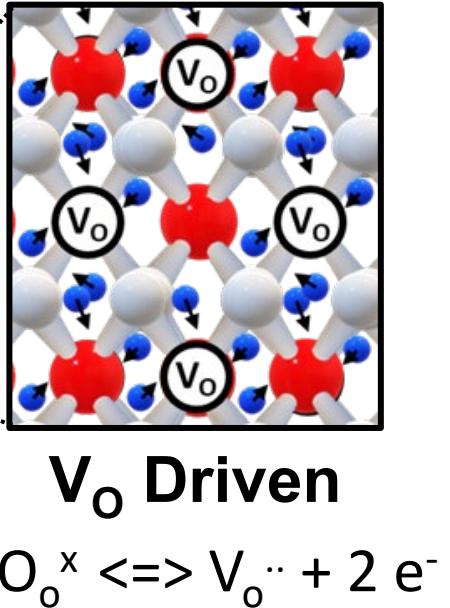
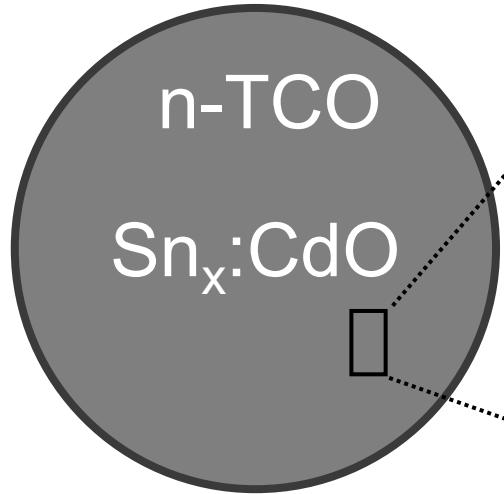


Knight shift ($\Delta\delta$)

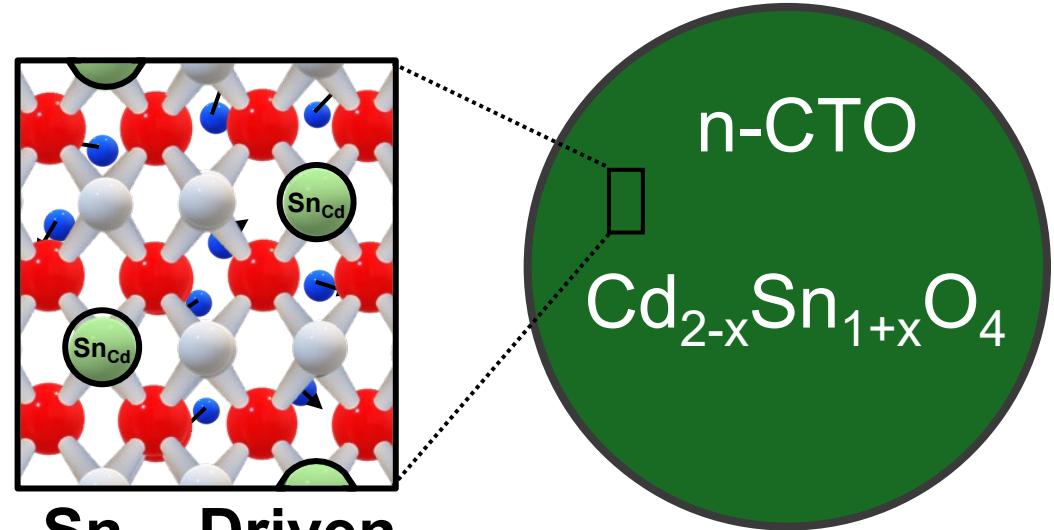
FWHM ($\Delta\nu$)



The ternary Cd – Sn – O PSNCs and the impact of structure on plasmonic properties



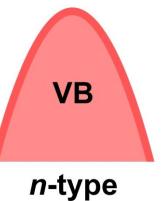
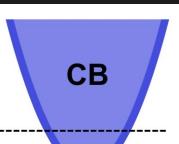
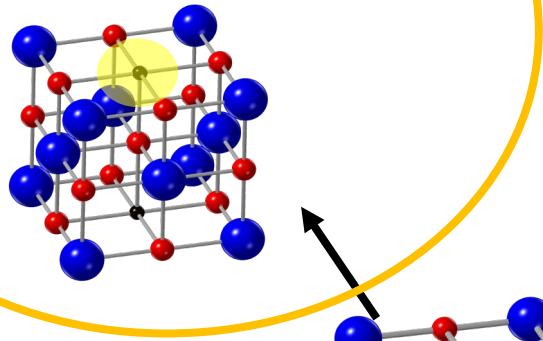
- Rock salt
- Sn(IV)
- V_O
- Carriers increase with x
- CdO = 0.26m_e



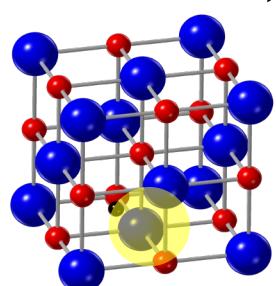
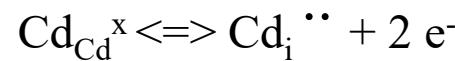
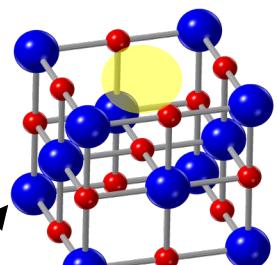
Sn_{Cd} Driven



- Inverted spinel
- Sn(IV)
- Sn_{Cd}
- Carriers increase with x
- Cd_{1.86}Sn_{1.14}O₄ = 0.022m_e

(antisite) M_{1M_2} 

x
y
z

 M_i  V_M 

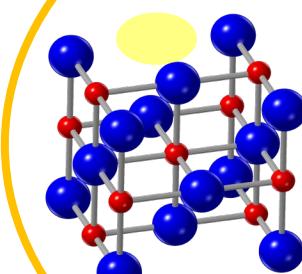
Defect Engineering

 $V_{M/O}$, M/O_i M_{2M_1}

carrier density

 $n \sim 10^{19} - 10^{21}$ carriers/cm³ MO_x

carrier mass

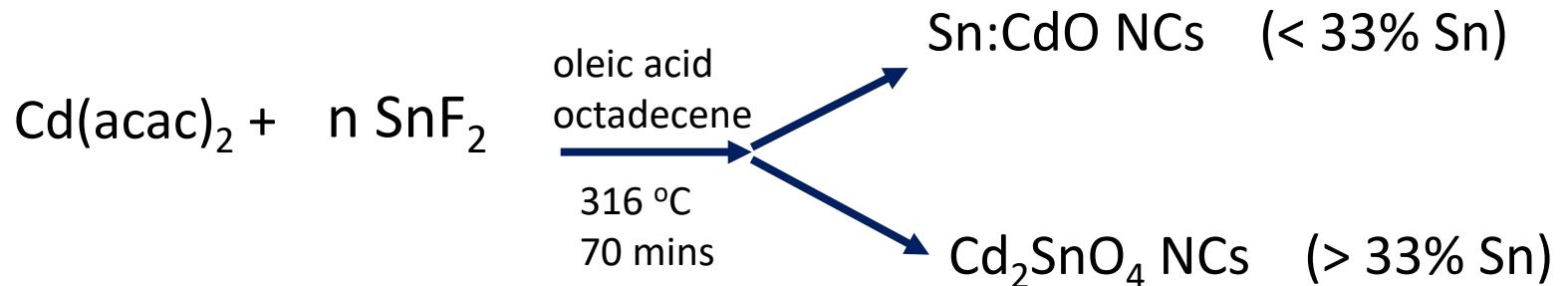
 $m^* \sim 0.01 - 2.0 m_e$ V_O 

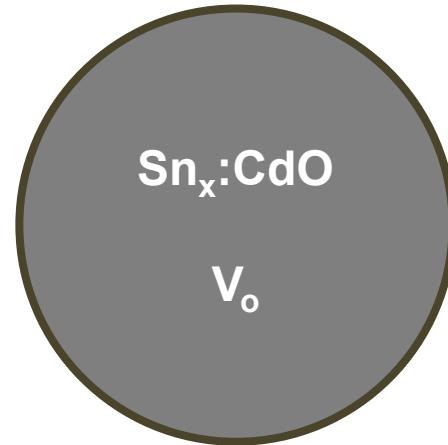
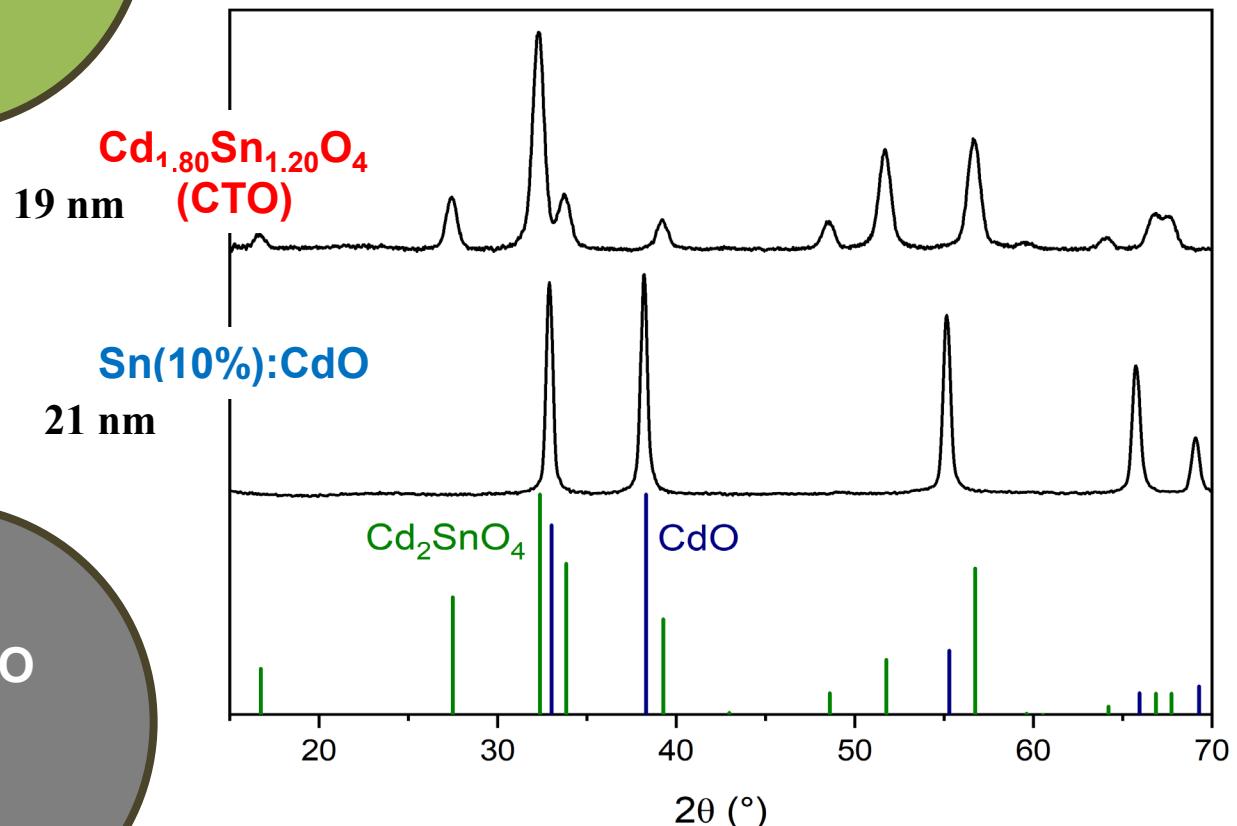
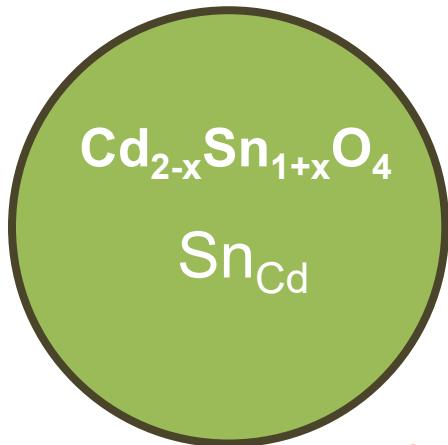


Sn:CdO (V_o carriers) Rock salt

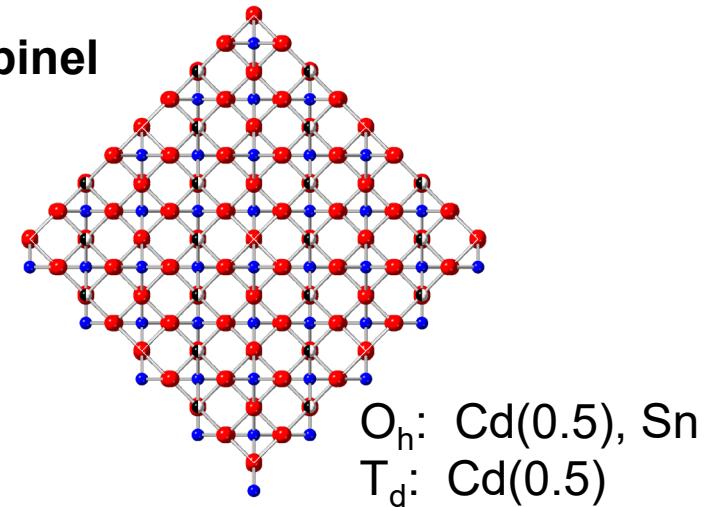
vs.

Cd_2SnO_4
(antisite carriers)
inverted spinel

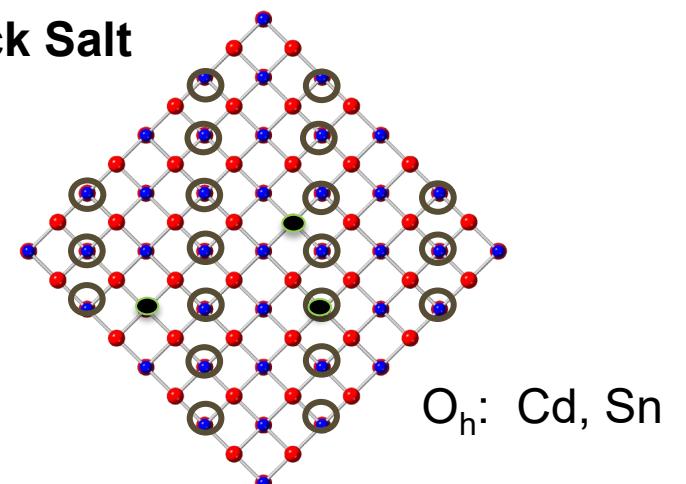


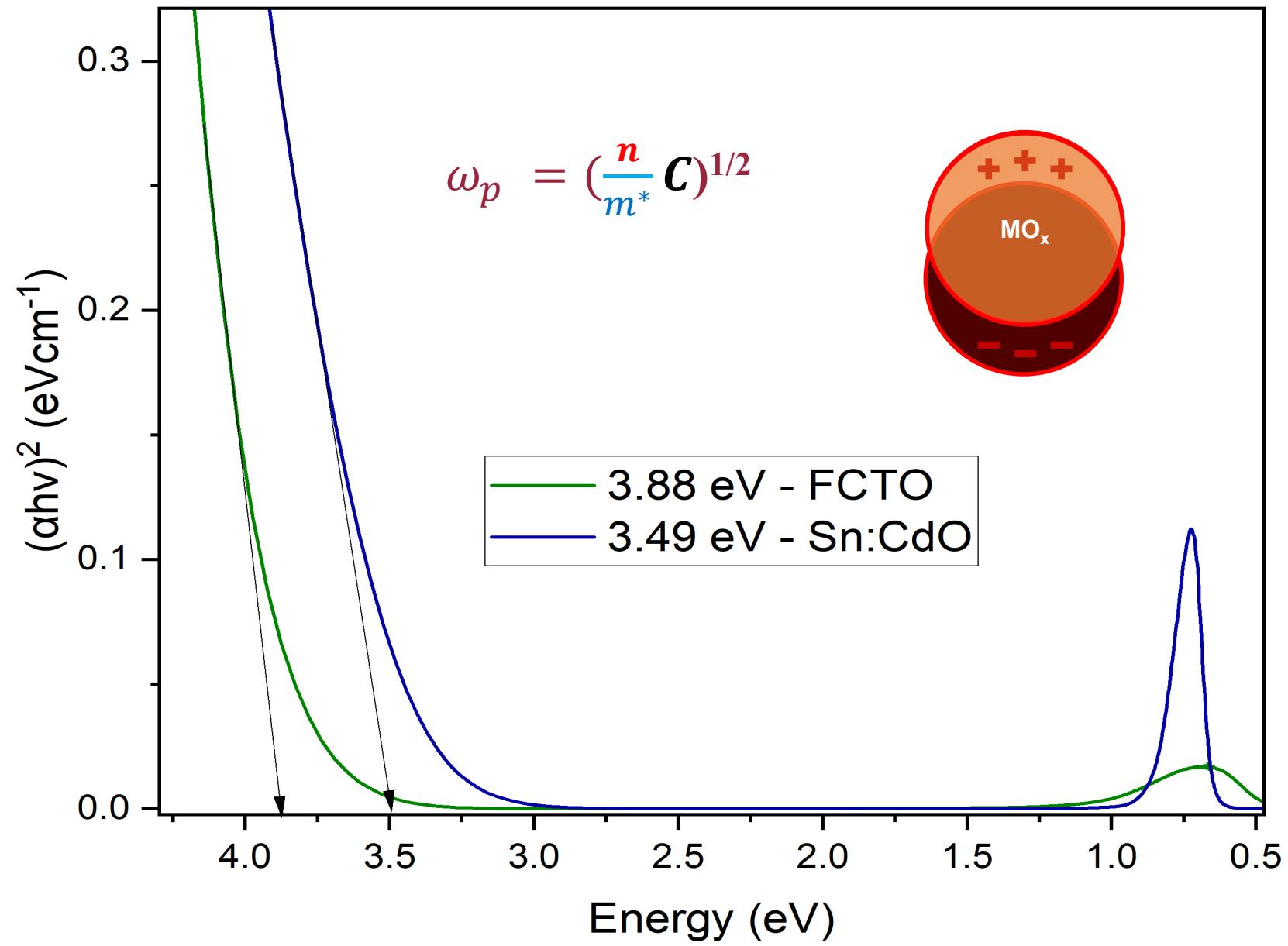
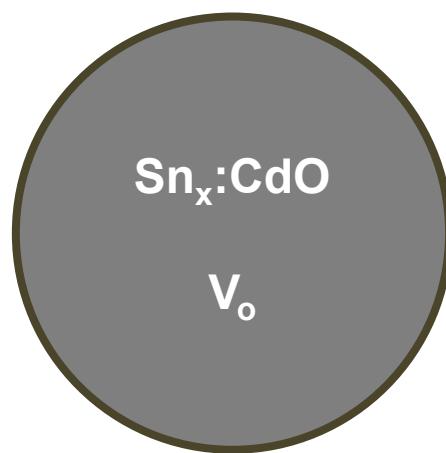
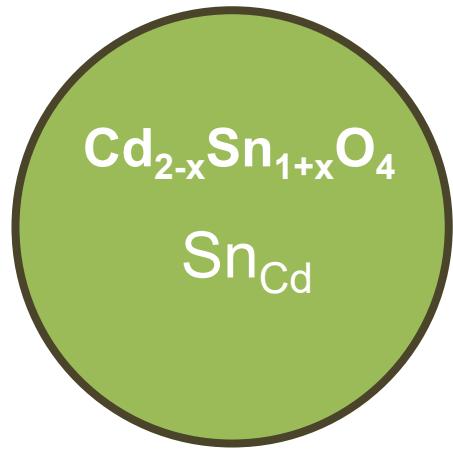


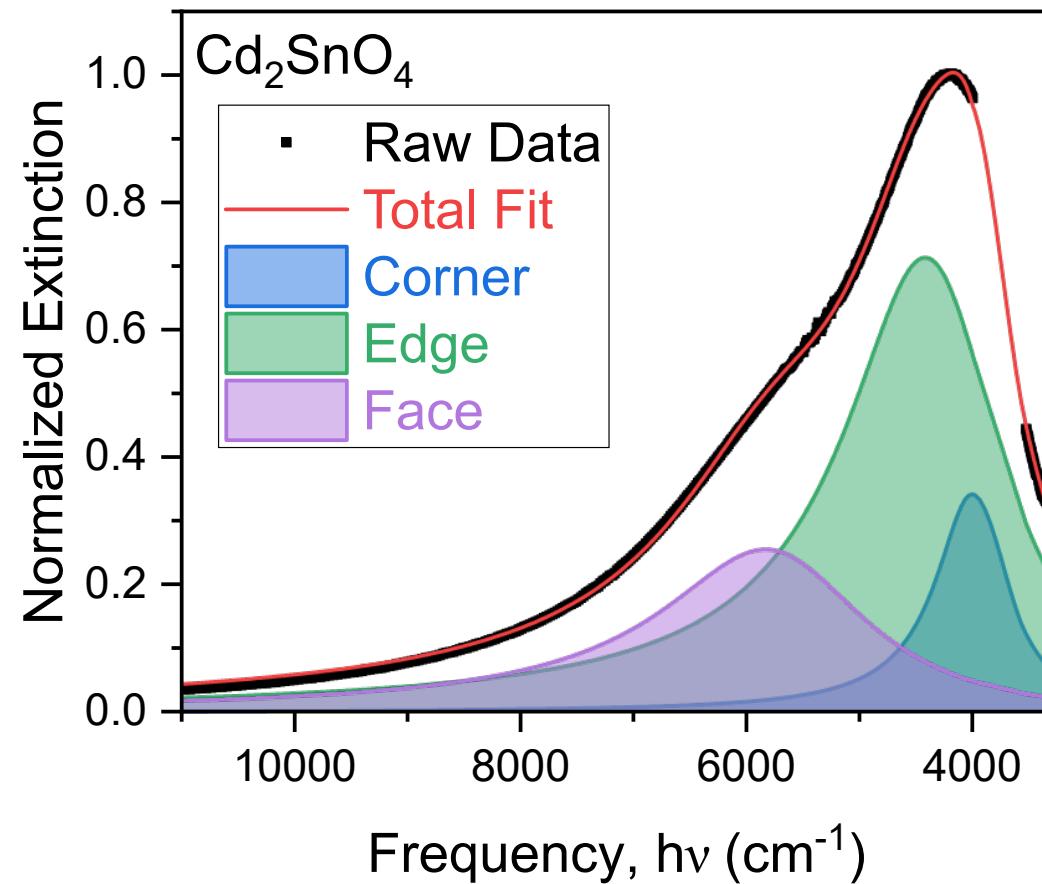
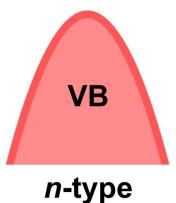
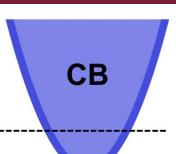
Inverted spinel



Rock Salt

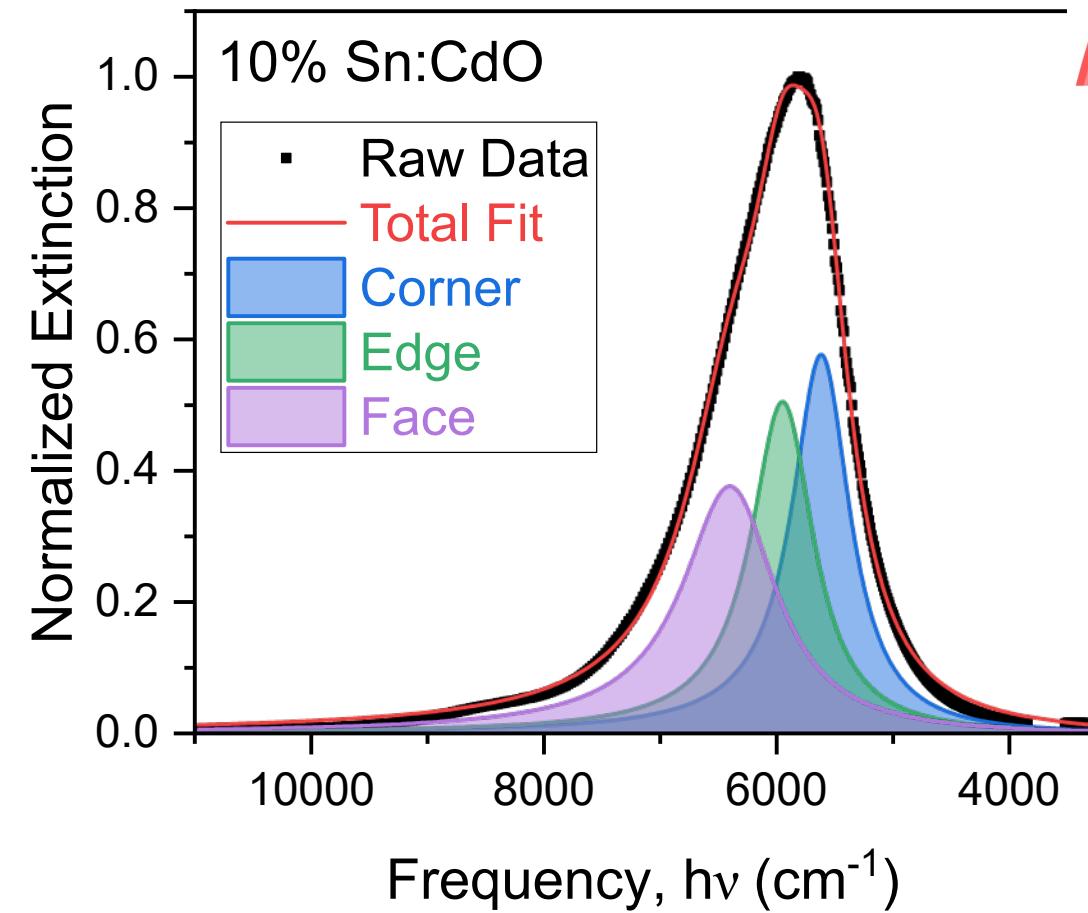






$$n = 5 \times 10^{19} \text{ carriers}/\text{cm}^3$$

$$m^*(\text{Lit}) = 0.022m_e$$



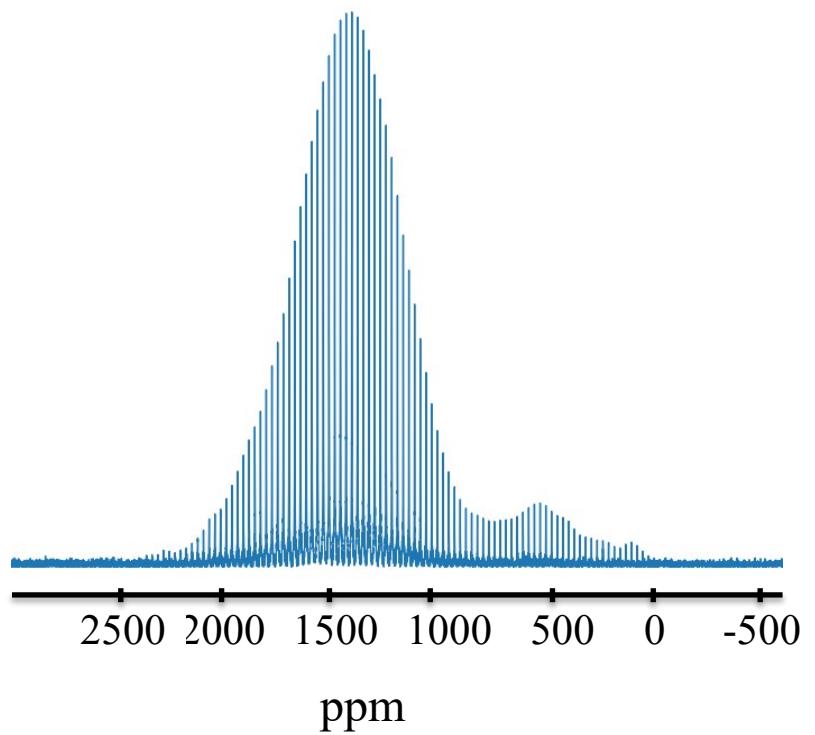
$$n = 1.5 \times 10^{21} \text{ carriers}/\text{cm}^3$$

$$m^* (\text{Lit}) = 0.26m_e$$

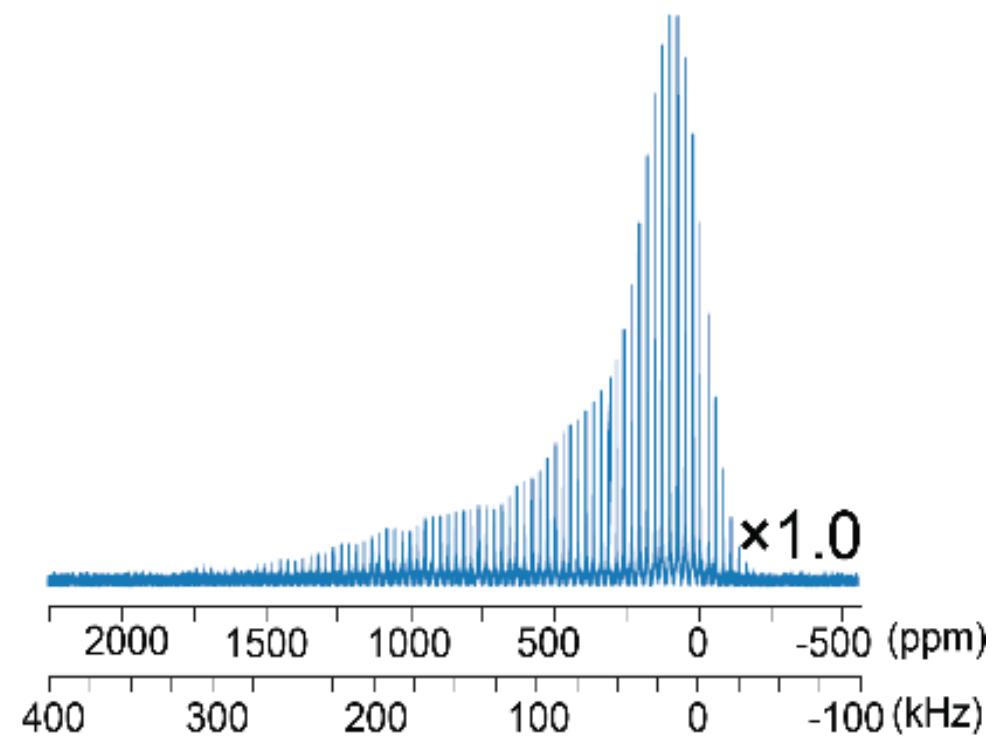


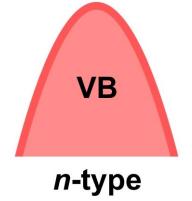
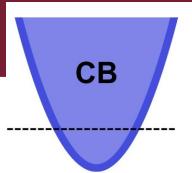
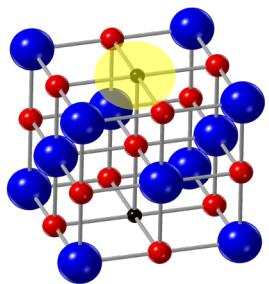
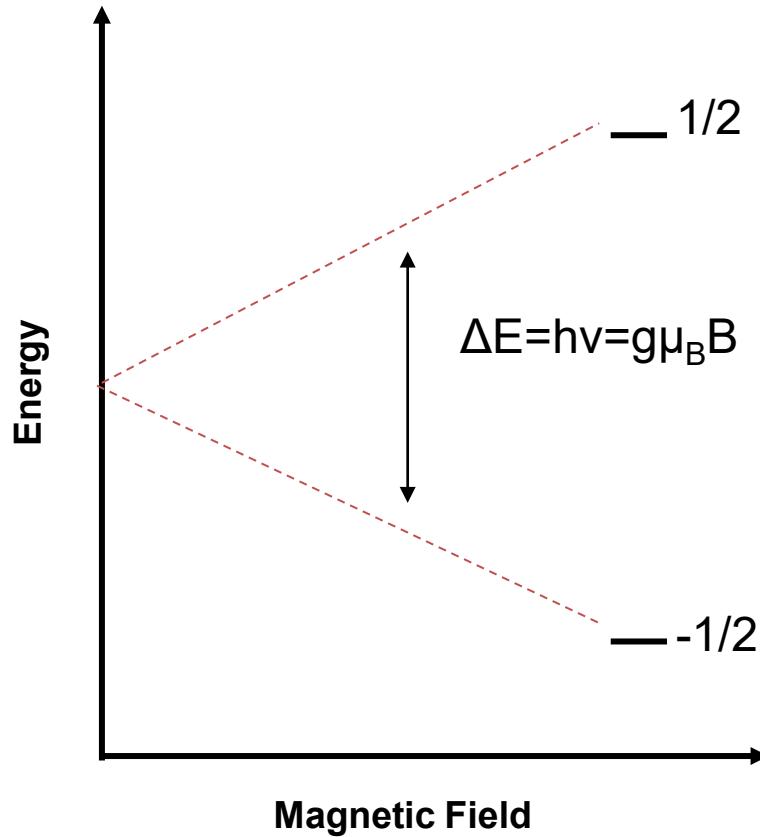
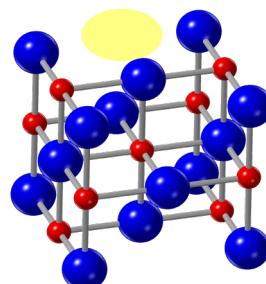
^{113}Cd solid state NMR to probe site dependent effect in Sn:CdO vs. CTO

^{113}Cd of 10% Sn:CdO PSNCs collected using a WURST-CPMG pulse sequence



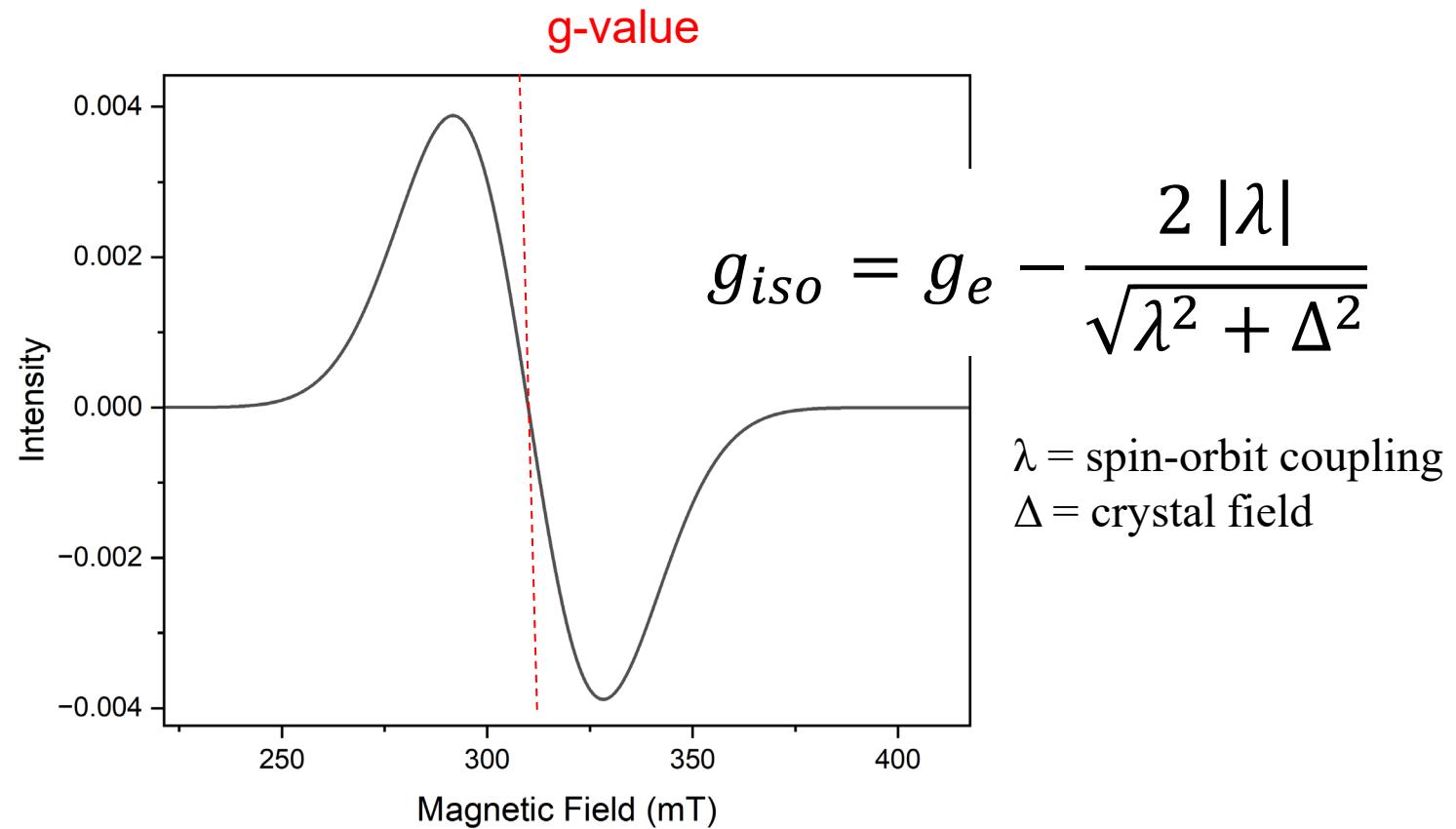
^{113}Cd of CTO PSNCs collected using a WURST-CPMG pulse sequence



(antisite) Sn_{Cd}V_O

Are the carrier parentage really different?

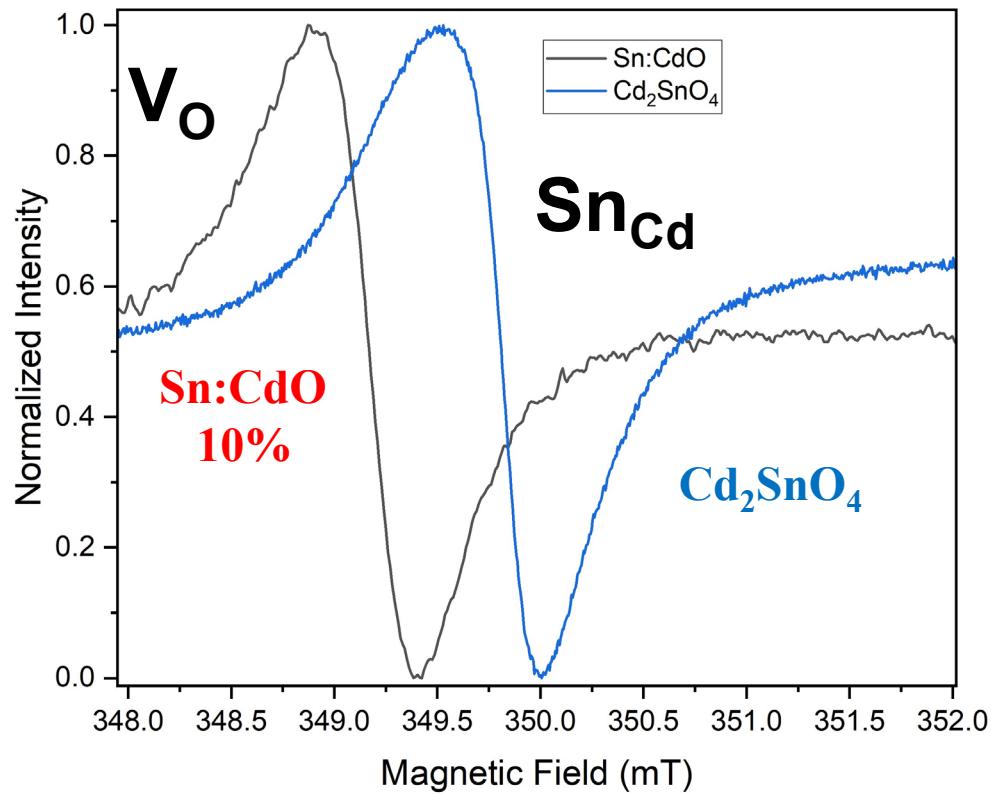
Electron Paramagnetic Resonance (EPR)





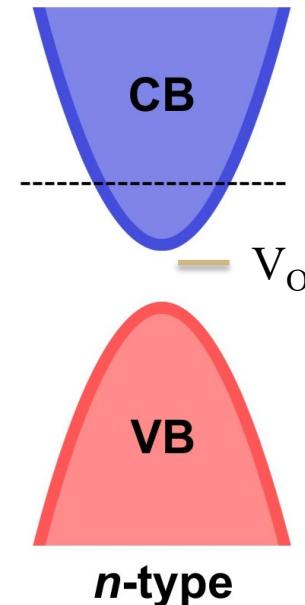
Identifying the defect type by EPR

(X-band, RT)



CdO Liu, Z. et al., ACS Nano., 2020

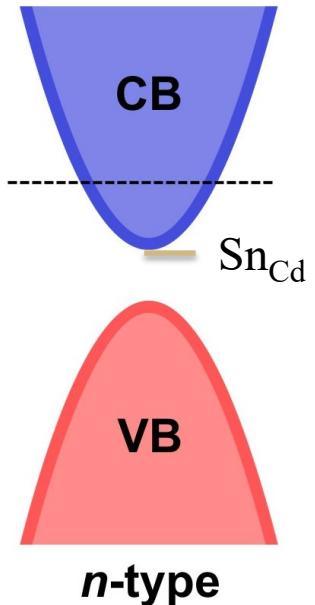
ZnO Ayoub, I. et al., Nanotechnol. Rev., 2022



$\text{Sn}(10\%):\text{CdO}$

V_O^\cdot

$g(\text{O}_\text{h}) \sim 2.005$



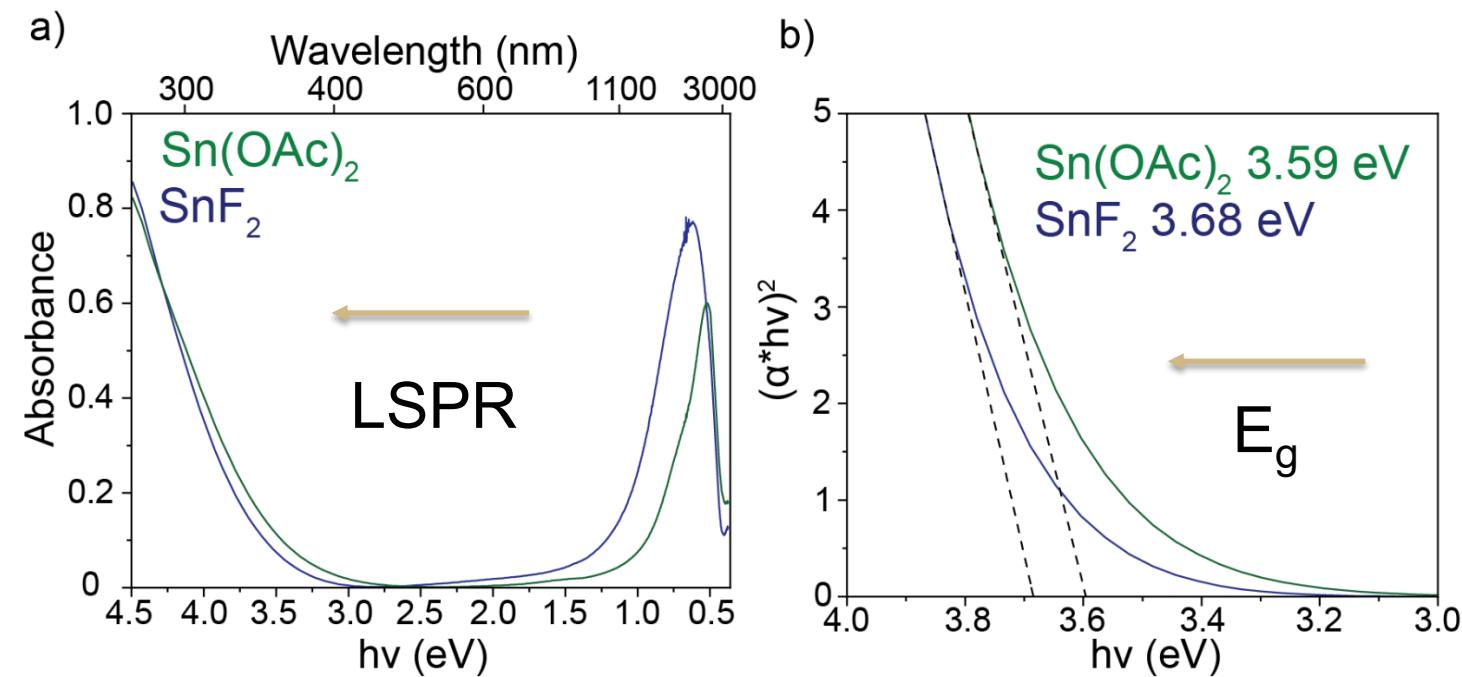
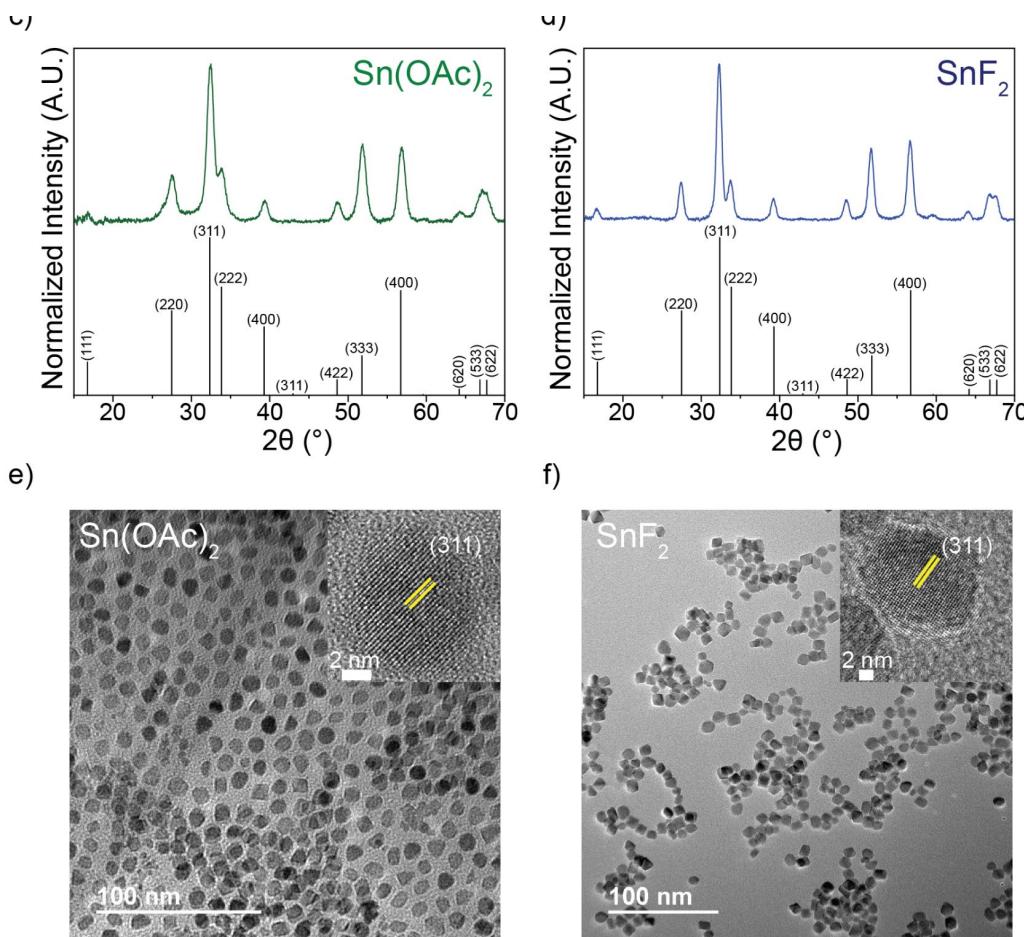
Cd_2SnO_4

Sn_{Cd}

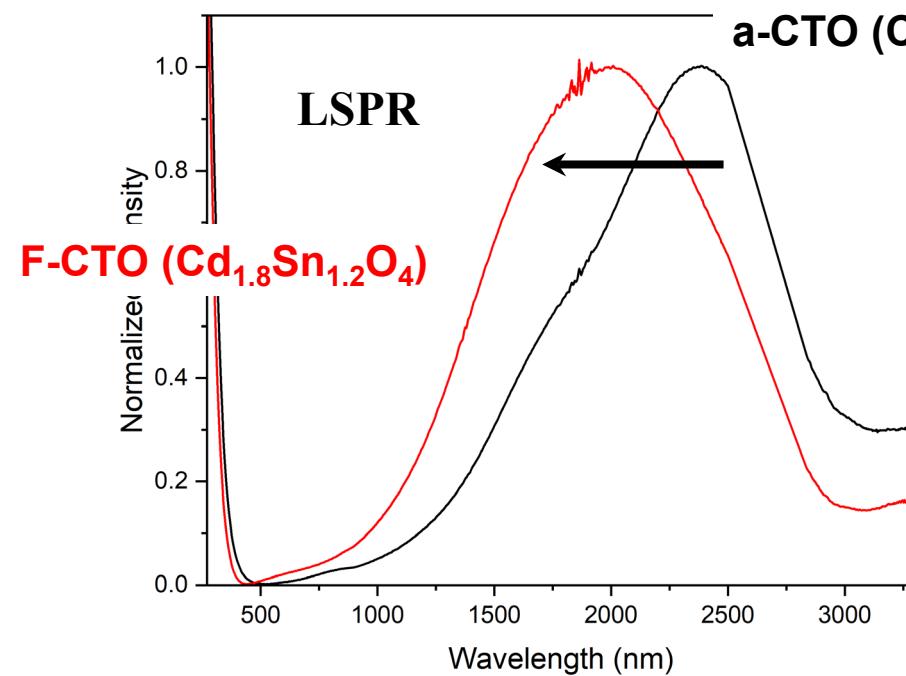
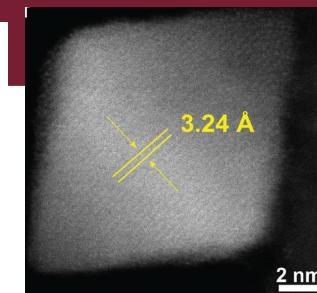
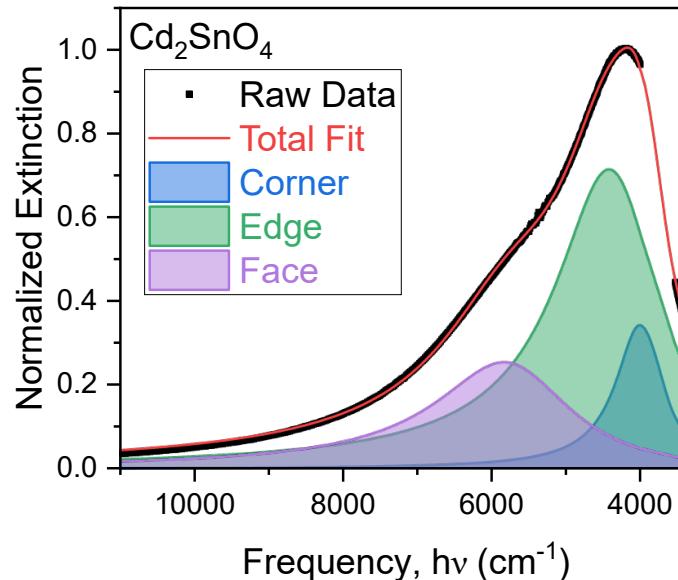
$g \sim 2.001$



Can we increase carrier densities by removal of V_o (Oxygen vacancy) by active etching using SnF_2 as reactant instead of $\text{Sn}(\text{acac})_2$?

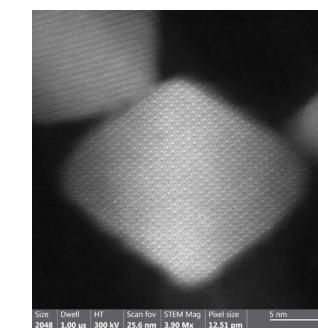
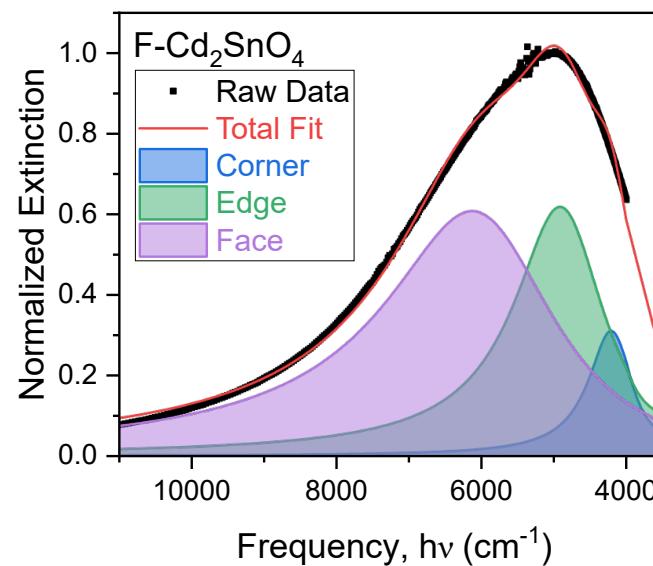


$$\omega_p^2 = \frac{ne^2}{m^* \epsilon_0} = \frac{n}{m^*} C$$

**a-CTO ($\text{Cd}_{1.86}\text{Sn}_{1.14}\text{O}_4$)**

Aspect ratio: 1.36

$$n = 5 \times 10^{19} \text{ carriers/cm}^3$$

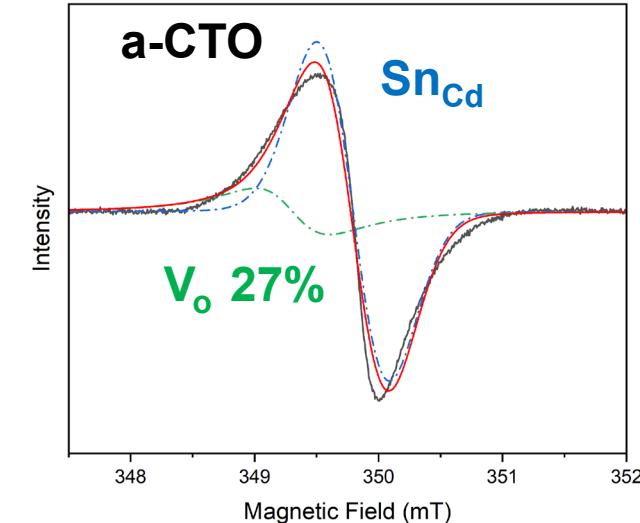
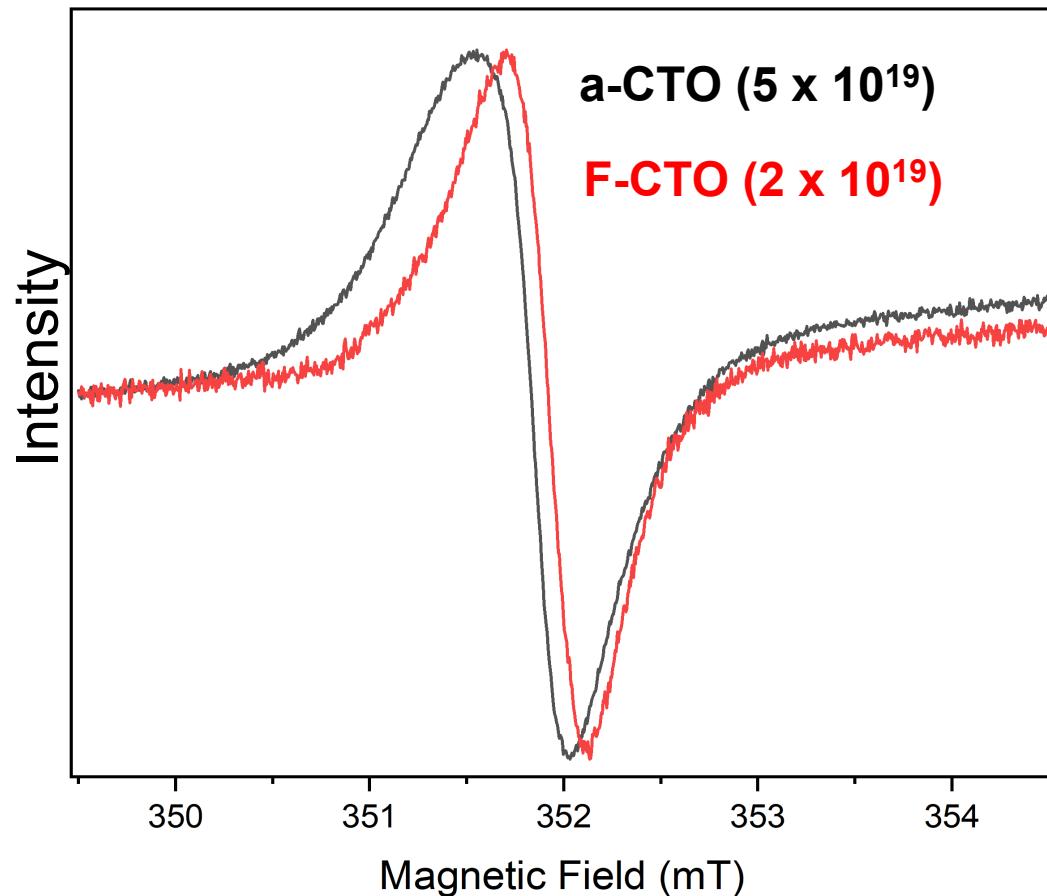
F-CTO ($\text{Cd}_{1.8}\text{Sn}_{1.2}\text{O}_4$)

Aspect ratio: 1.22

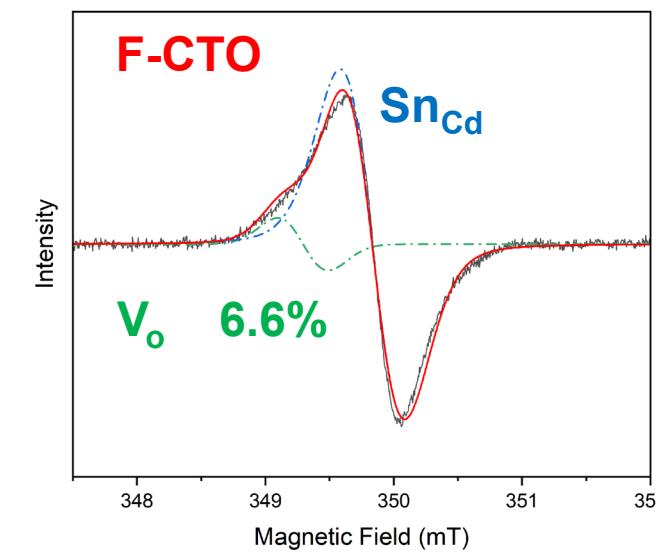
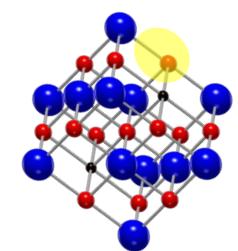
$$n = 2 \times 10^{19} \text{ carriers/cm}^3$$



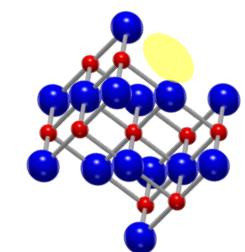
Does EPR help us understand?



Sn_{Cd}
 $g \sim 2.001$



V_o
 $g(O_h) \sim 2.005$



EPR confirms lower V_o for F-CTO, but why no increase in n ?

^{113}Cd – WURST

FCTO

$$\Gamma(\text{KS}) = 450\text{KHz}$$

$$2.0 \times 10^{19}$$

$$6\% V_O$$

$$B_0 = 18.8 \text{ T}$$

$$v_0 = 177.371 \text{ MHz}$$

$$v_{\text{rot}} = \text{static}$$

$$D1 = 6 \text{ sec}$$

$$D6 = 100 \mu\text{s}$$

50 Echoes

WURST SWEEPT = 600 kHz

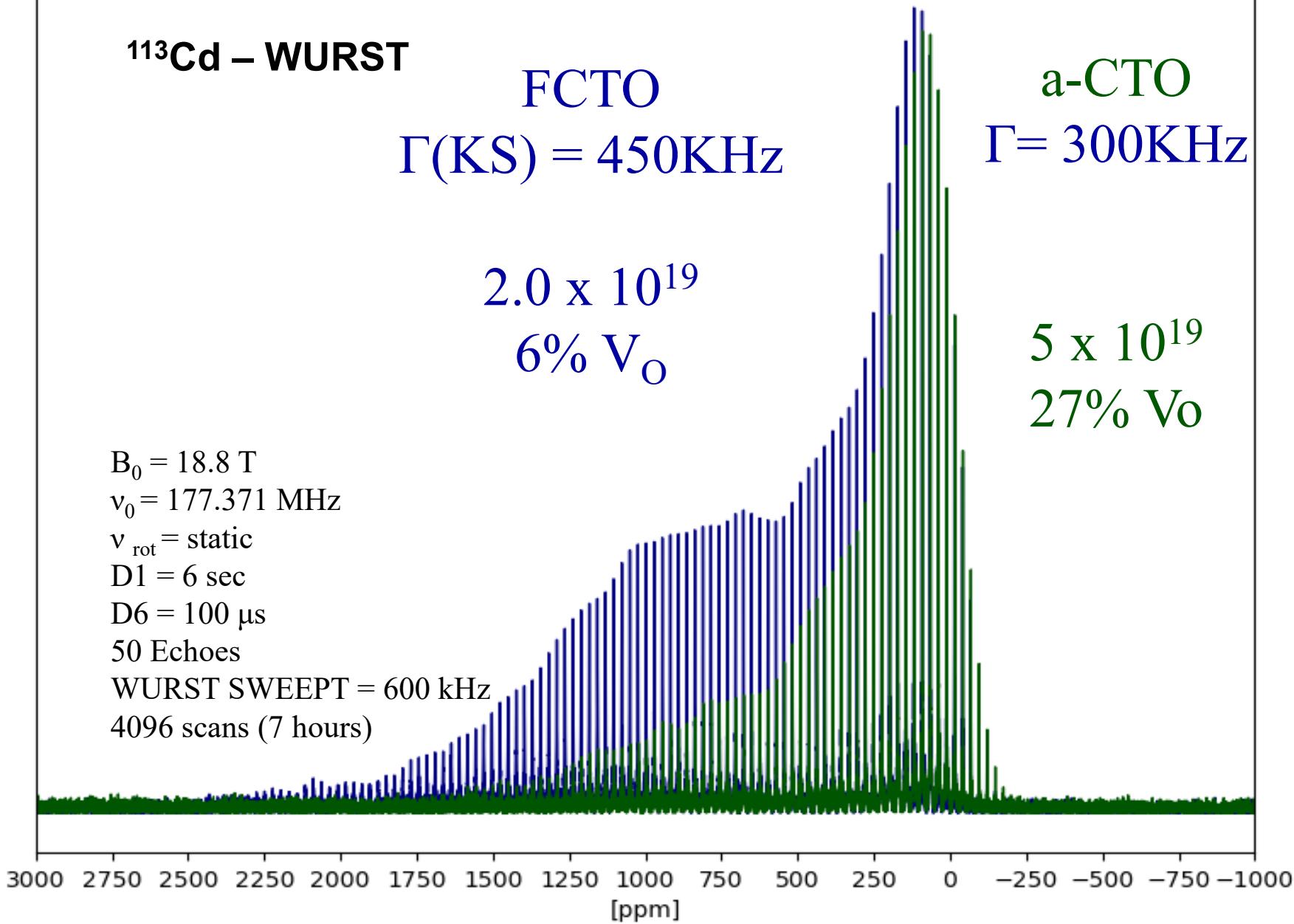
4096 scans (7 hours)

a-CTO

$$\Gamma = 300\text{KHz}$$

$$5 \times 10^{19}$$

$$27\% V_O$$



Observe a large increase in Knight Shift (KS)

$$KS \propto n^{1/3}$$

FCTO has lower carrier density but also lower V_O

$$V_O$$

Slower relaxation, T_1
Knight-Korringa



FLORIDA STATE
UNIVERSITY

But are we sure its KS and not CS?

a

800 MHz

b

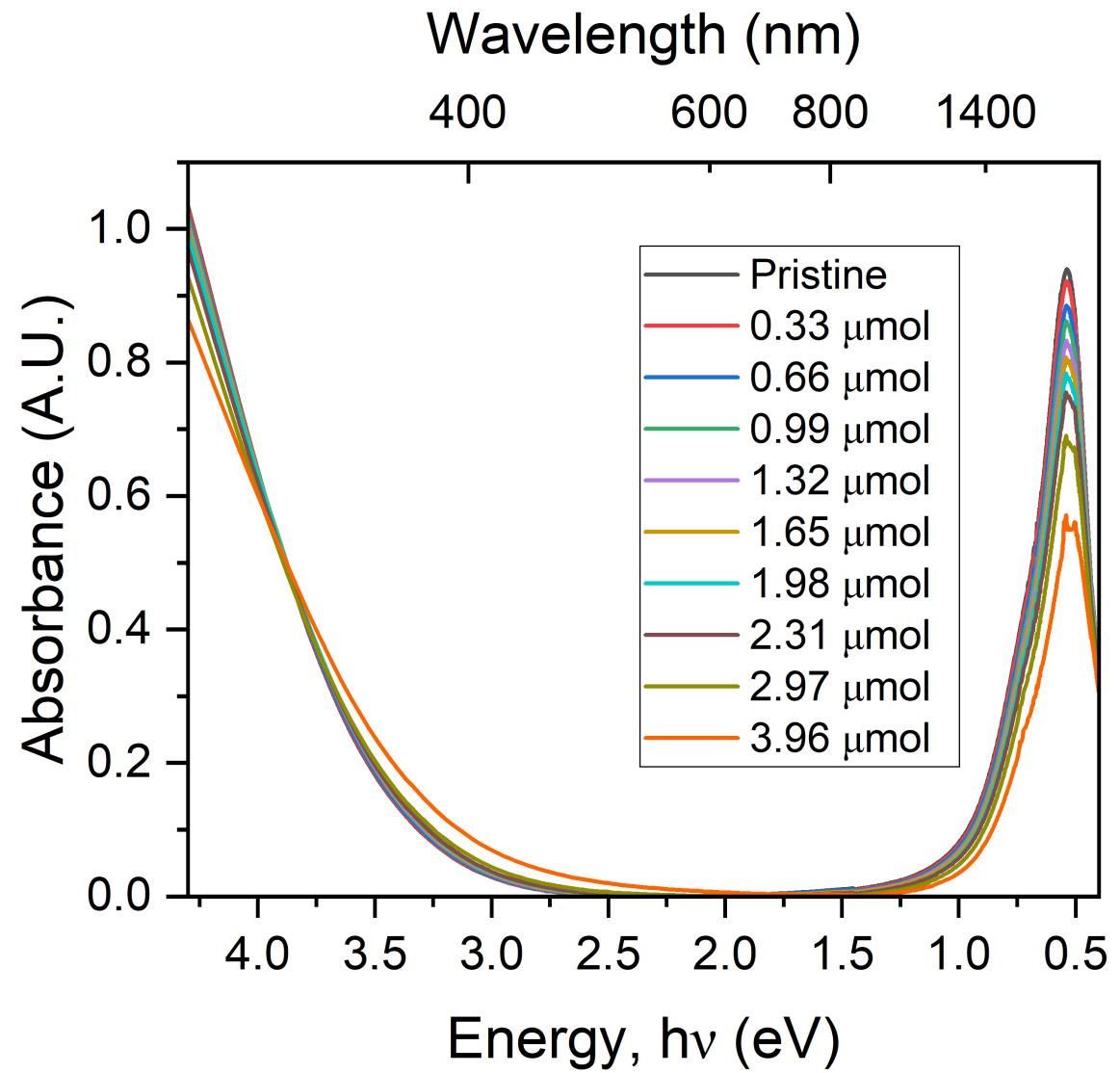
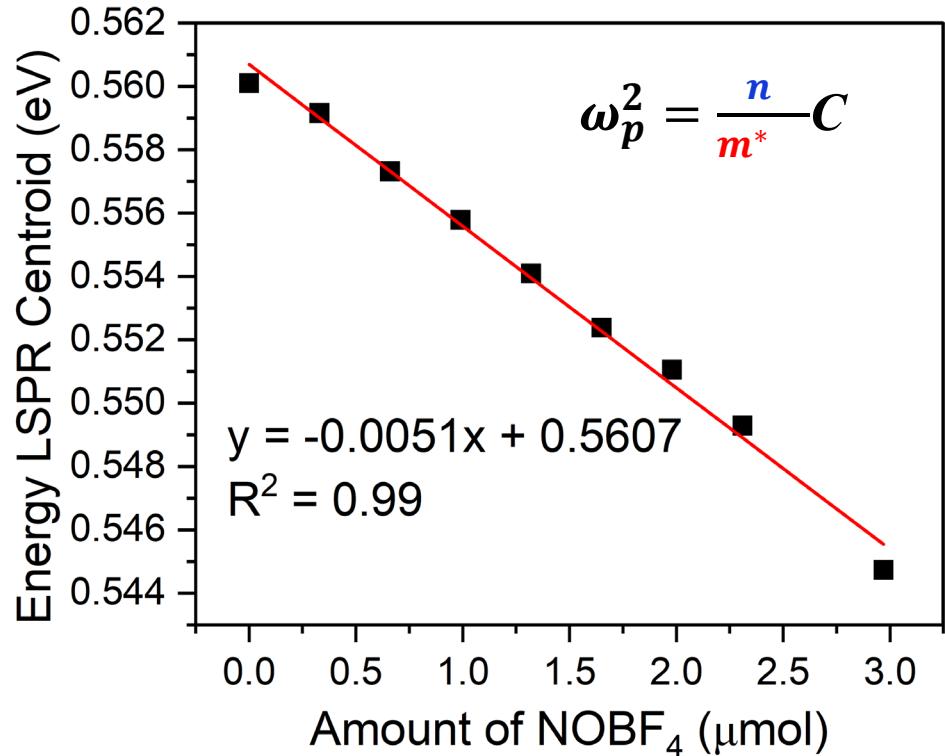
600 MHz



KS frequency shift
will be dependent
on applied field



Can we prove it by chemically removing carriers in CTO using the 1-electron oxidant NOBF_4 ?

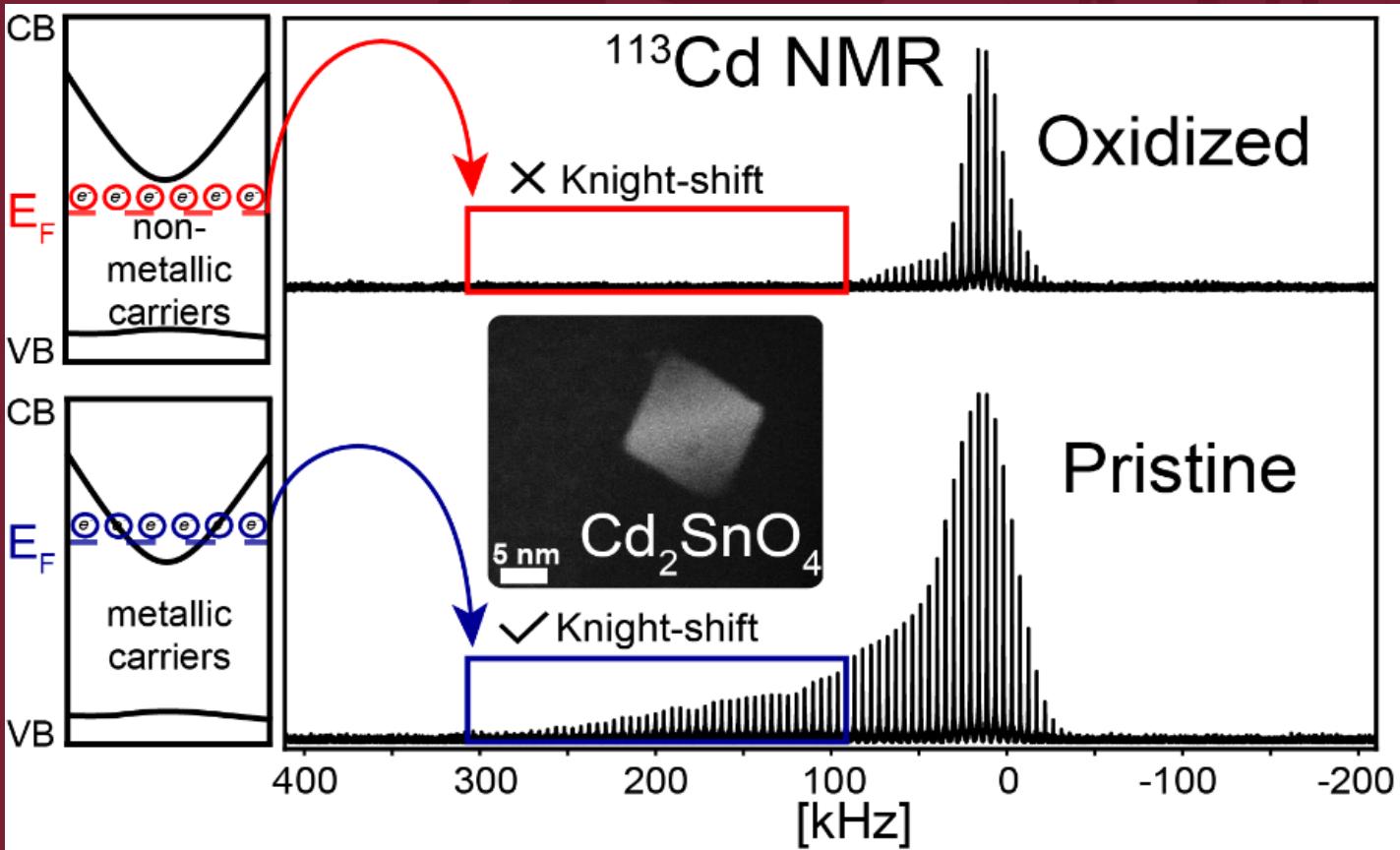




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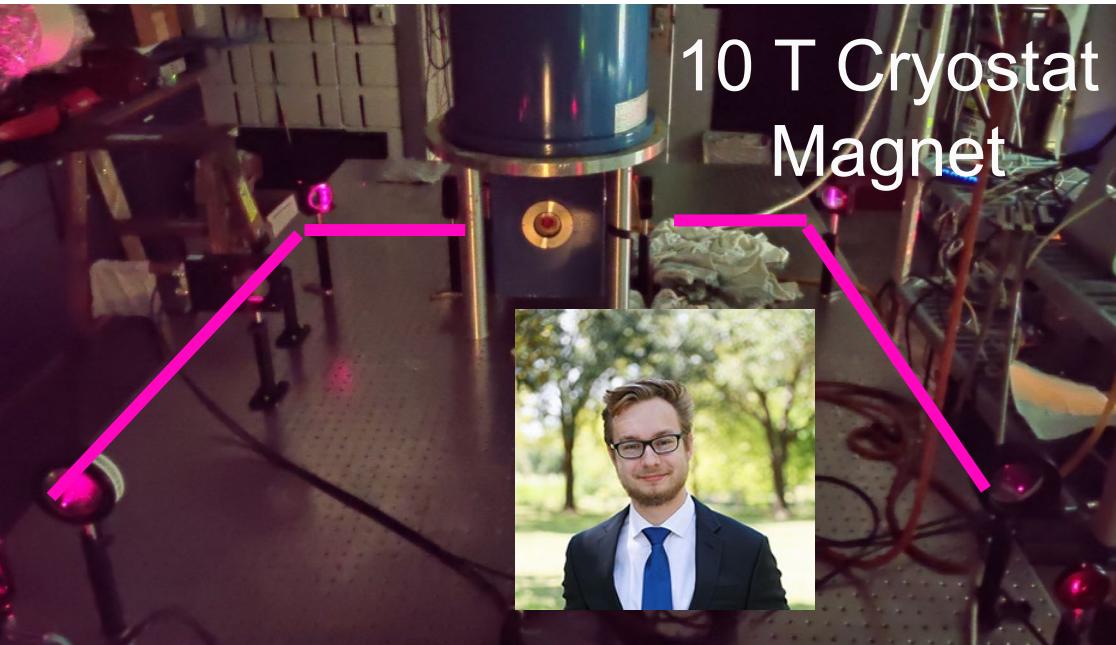
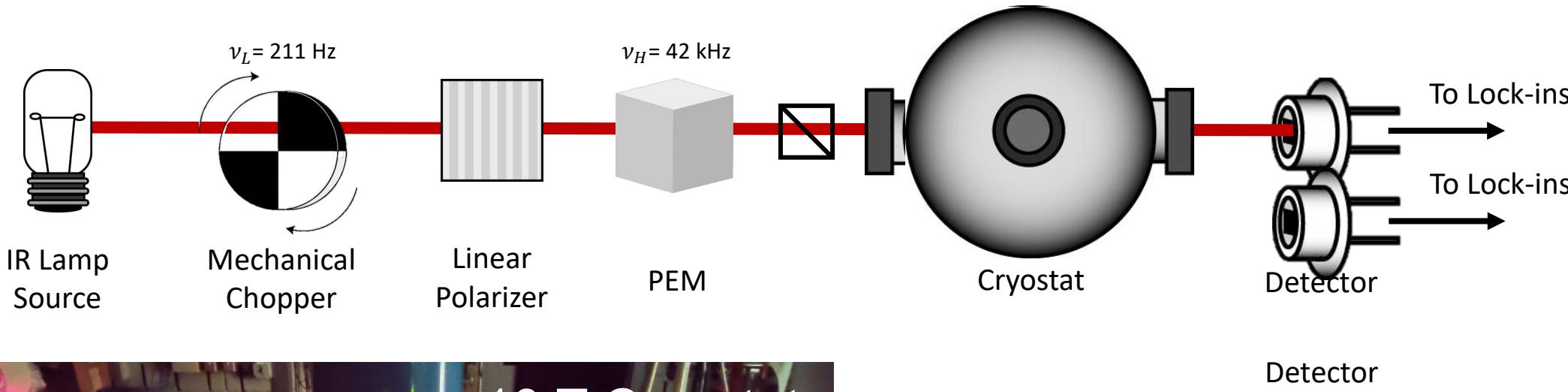
Can we be sure it is KS and not CS?

F-CTO Titrated with NOBF_4



Spectral change suggests shift arises from metallic like carriers (Knight shift) since CS is site dependent
 $KS \propto n^{1/3}$

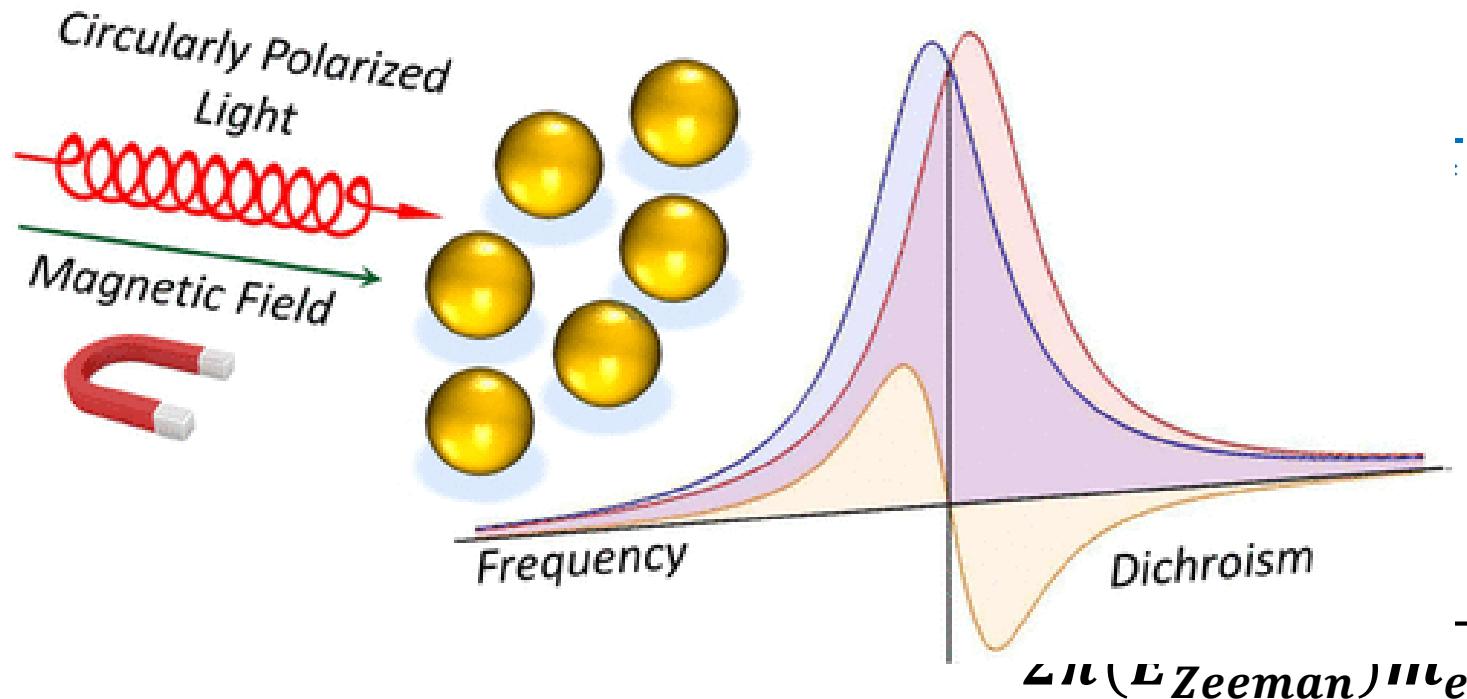
VT, VH-MCD Experiment



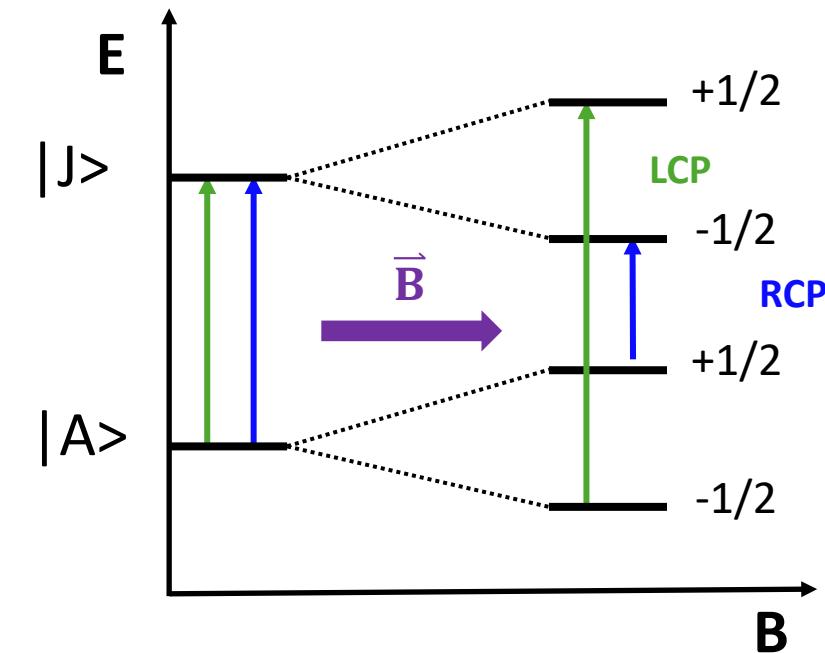
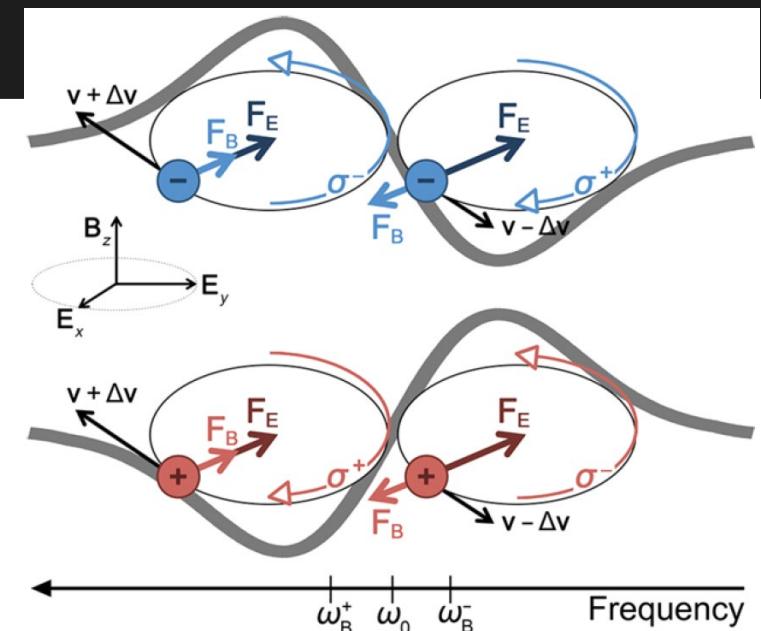
Magnetic Circular Dichroism (MCD)

Extraction of m^*

Cyclotron resonance



$$\omega_c = \frac{qB}{m^* m_e}$$

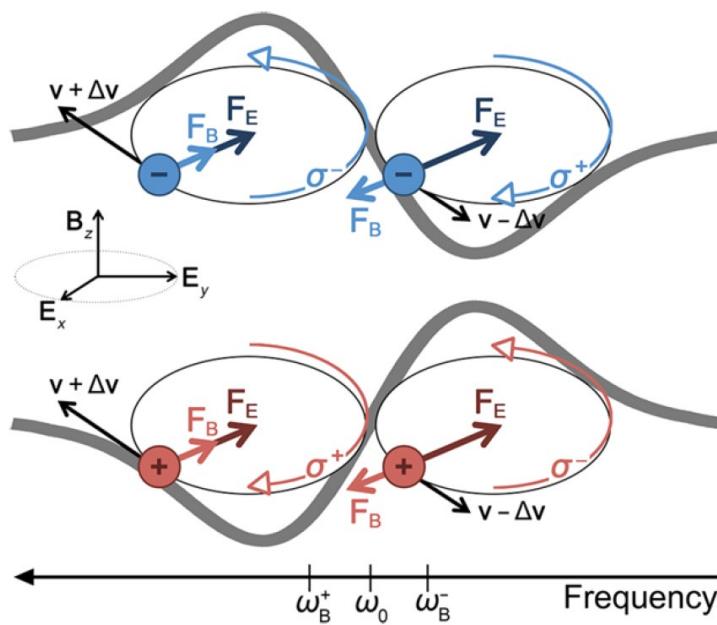
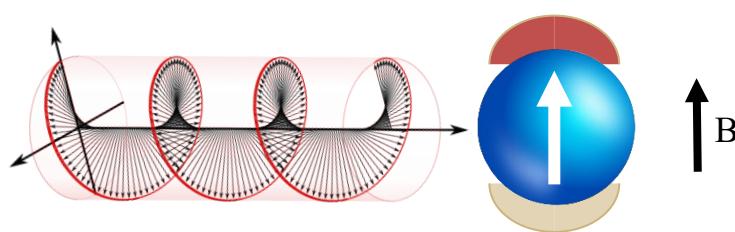


1. Pineider, F. et al, *Nano Lett.* **2013**
2. Hartstein, K. H. et al., *J. Phys. Chem. Lett.* **2017**
3. Kimura, T. and Hiroshi, Y., *J. Phys. Chem. C* **2022**



Is this a question of trapping at donor levels due to V_O ?

Then it should be reported as a change in m^* measured by MCD



$$\omega_B^{LCP/RCP} = \omega_0 \pm \frac{qB}{2m^*}$$

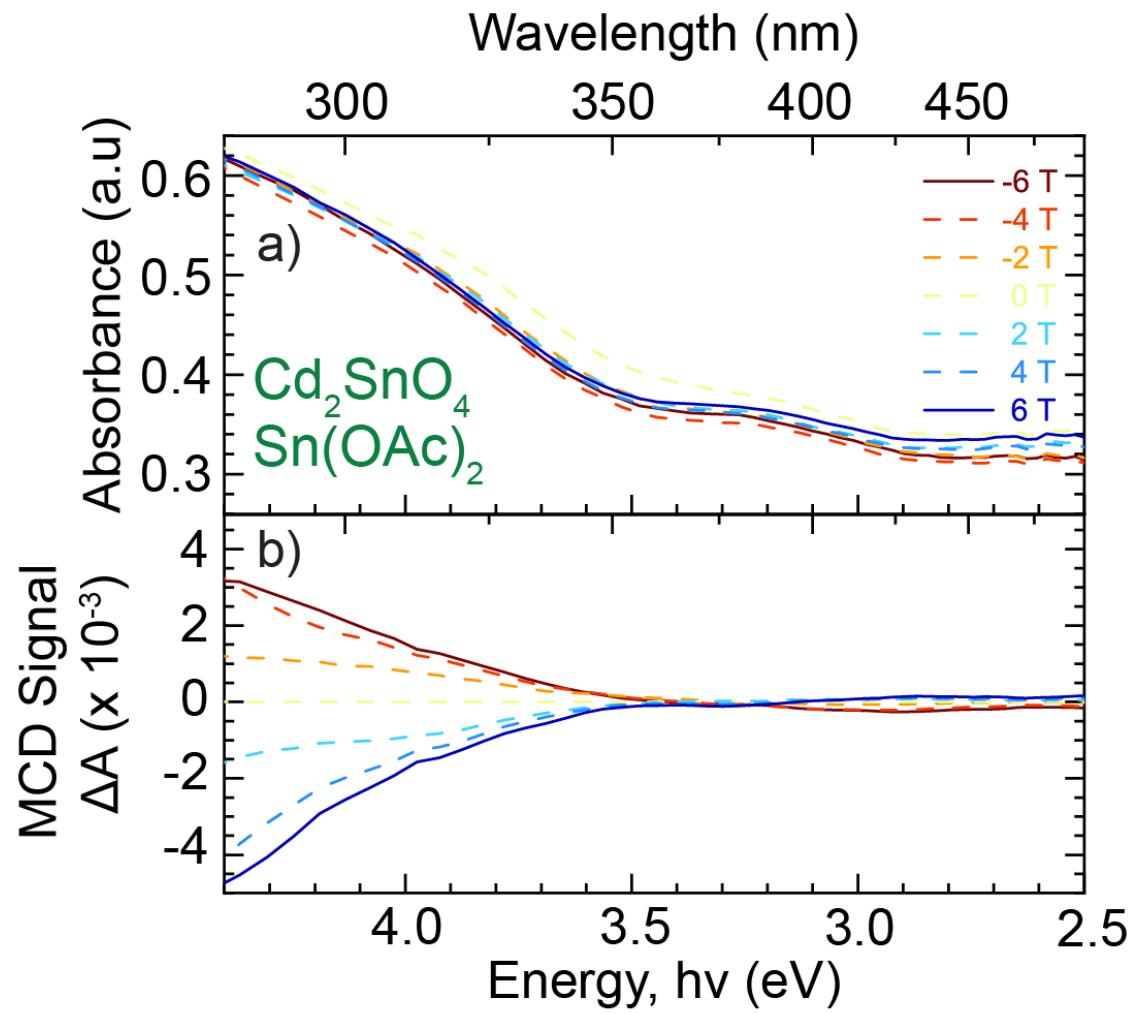
$$m^* = \frac{qBc}{2\pi(E_{Zeeman})m_e}$$

Pineider, F. et al, *Nano Lett.* **2013**

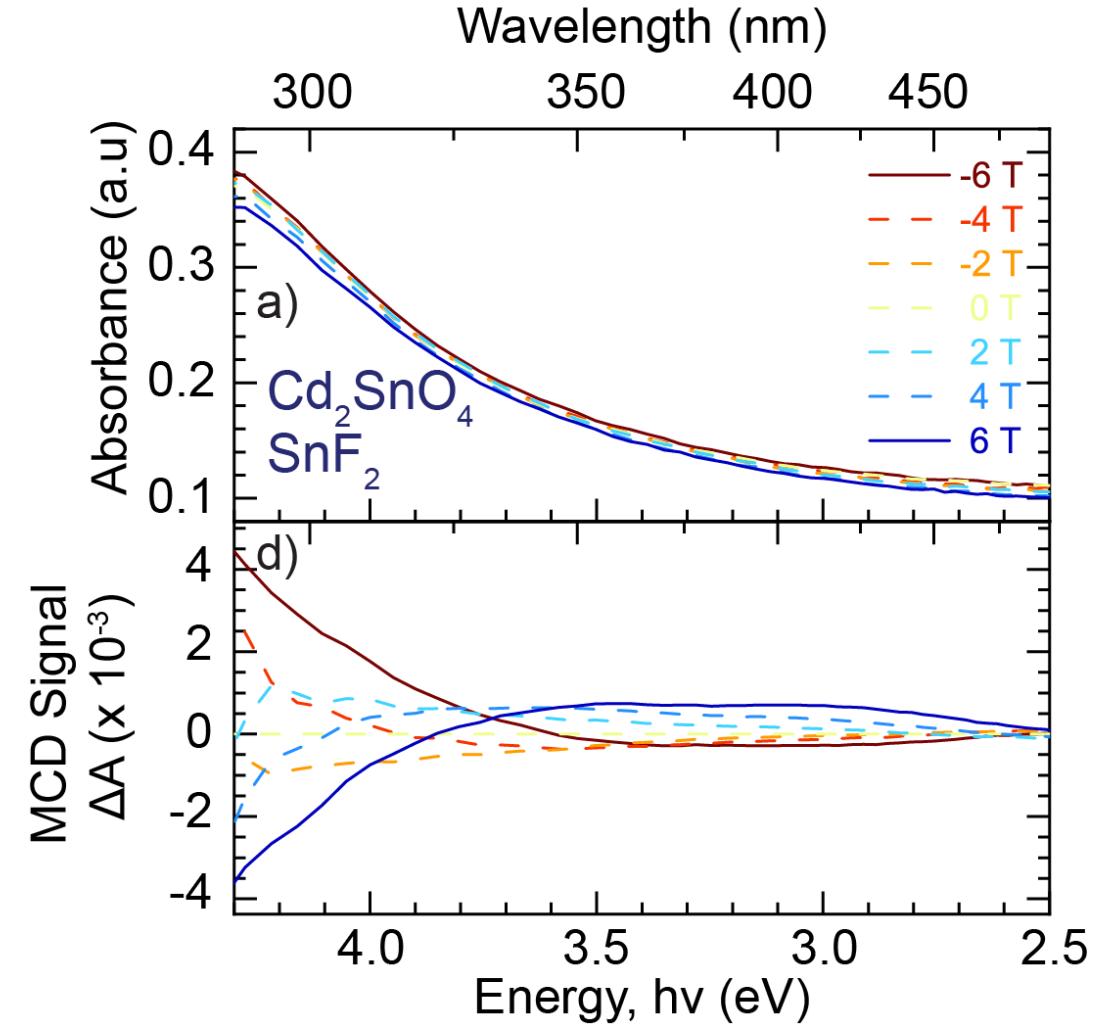
Hartstein, K. H. et al., *J. Phys. Chem. Lett.* **2017**

Kimura, T. and Hiroshi, Y., *J. Phys. Chem. C* **2022**

Kuszynski, J., et al *J. Phys. Chem. C* **2022**



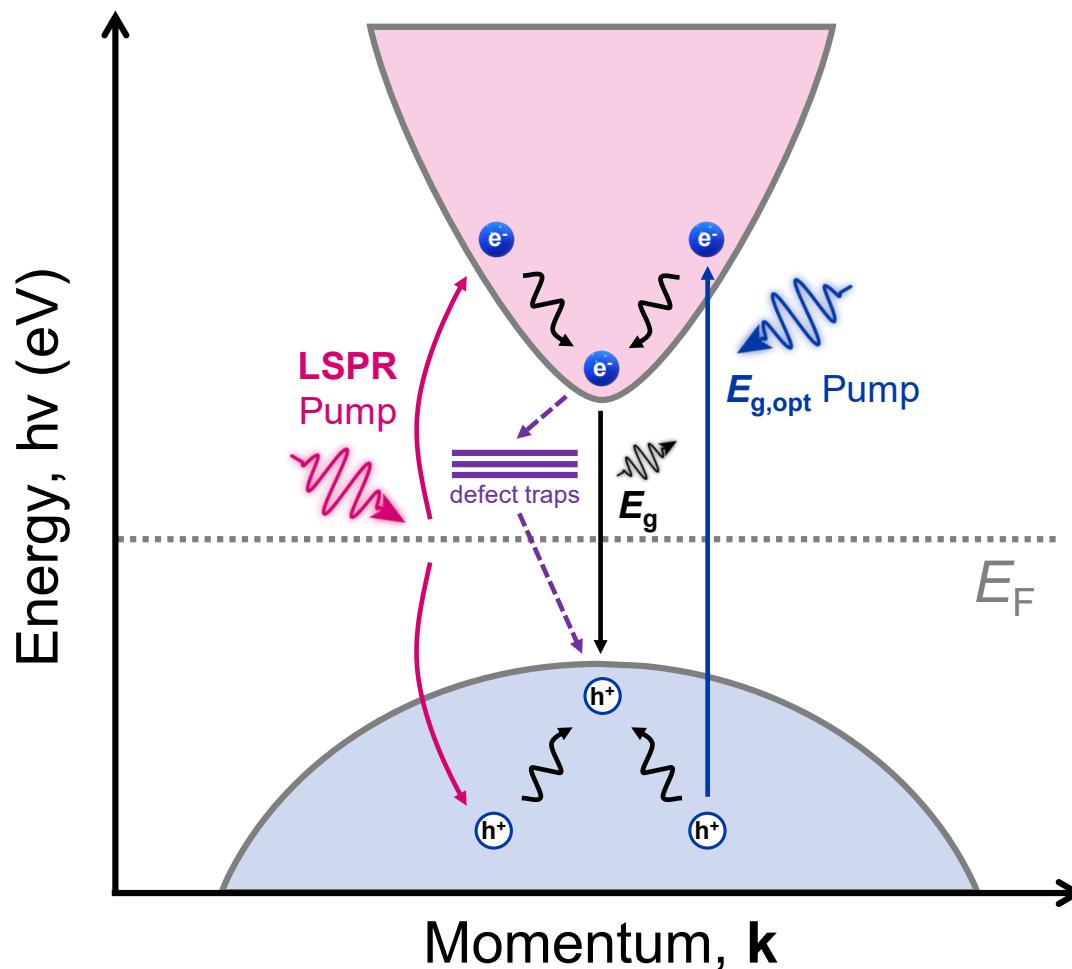
0.022 m* for a-CTO



0.006 m* for F-CTO

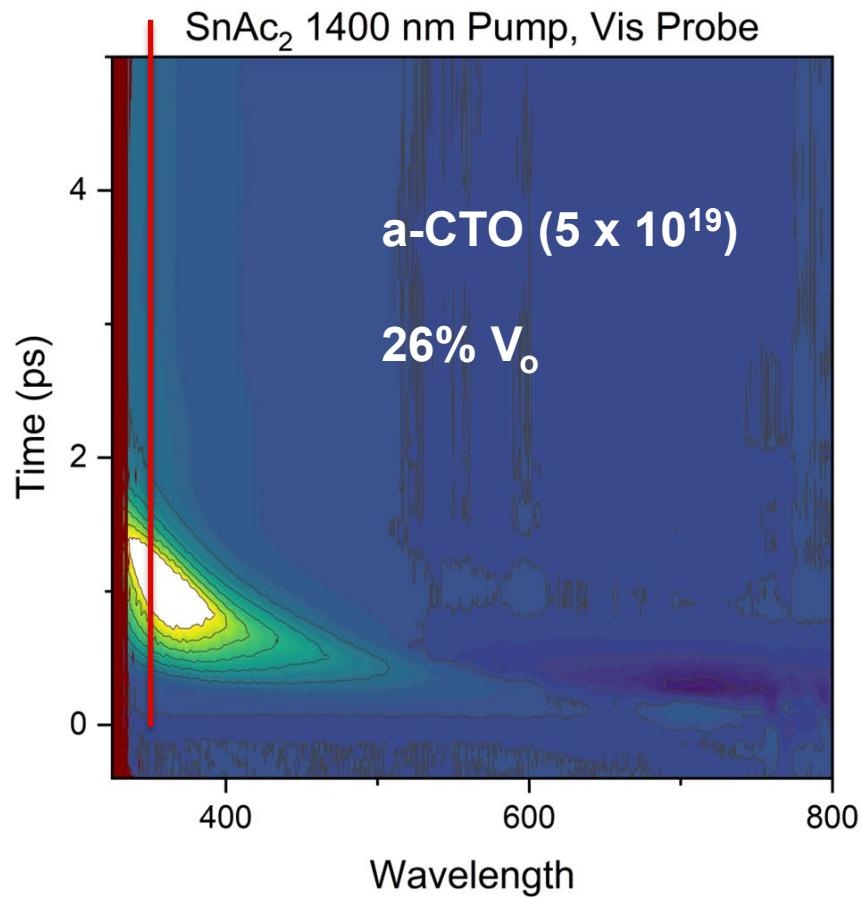


It will also show up in the LSPR Relaxation Processes

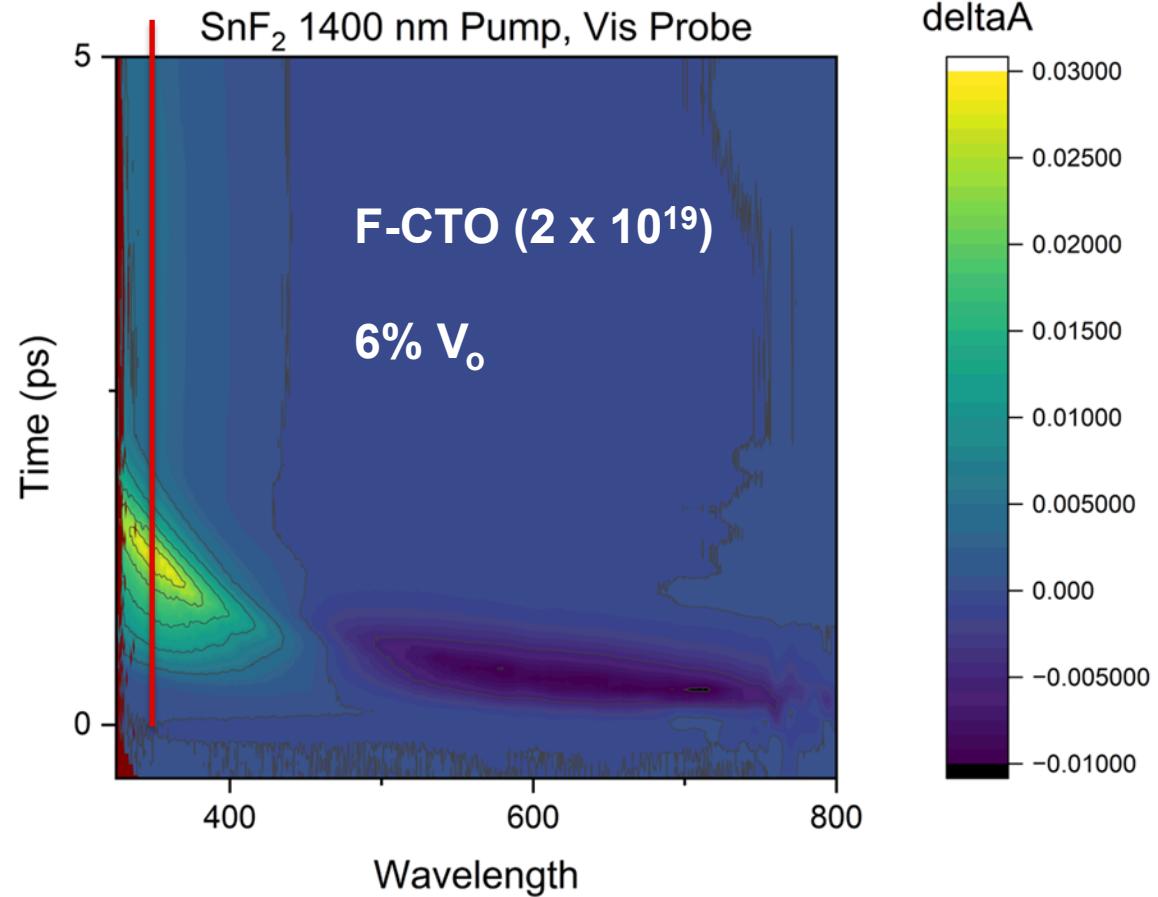




Cd₂SnO₄ fs-TA Data



350 nm Probe (0.99+ R ² Fits)		
LSPR Pump	Decay (fs)	Decay (ps)
SnAc ₂	184.0 ± 5.8	27.19 ± 3.95
SnF ₂	192.2 ± 6.4	99.51 ± 53.51





SMART
SCIENCE, MATHEMATICS,
AND RESEARCH FOR
TRANSFORMATION
PART OF THE NATIONAL
DEFENSE EDUCATION PROGRAM

NSF-DMR #1905757

- $S_{n_{cd}}$ or V_O results in change in carrier mobility
 - (XPS, XSTM, TA, NMR and EPR T_1 and T_2)
- Site and lattice matter (lattice energies) – DFT
- Impacts w_d – surface interface damping
- Impacts LSPR damping/ hot carrier formation
- **Way more to do to fully understand carrier parentage in a PSNC**
shape, concentration, chemical interface damping, T-dependence,

Does carrier parentage matter?

